

A new approach to build a low-level malicious fault list starting from high-level description and alternative graphs

Benso, A.; Prinetto, Paolo; Rebaudengo, M.; Sonza, M.; **Ubar, Raimund-Johannes** Proceedings IEEE European Design & Test Conference, Paris, March 17-20, 1997 1997 / p. 560-565 <https://ieeexplore.ieee.org/document/582417>

About robustness of test patterns regarding multiple faults

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan LATW 2012 : 13th IEEE Latin-American Test Workshop proceedings : April 10th-13th, 2012, Quito, Ecuador 2012 / p. 86-91 : ill <https://www.infona.pl/resource/bwmeta1.element.ieee-art-000006261243>

Accelerating transient fault injection campaigns by using Dynamic HDL Slicing

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Raik, Jaan; Sauer, Christian 2019 IEEE Nordic Circuits and Systems Conference (NORCAS) : NORCHIP and International Symposium of System-on-Chip (SoC), 29-30 October 2019, Helsinki, Finland : proceedings in IEEE Xplore 2019 / 7 p. : ill <https://doi.org/10.1109/NORCHIP.2019.8906932>

Active power losses in Estonian power transmission network

Ainsaar, Karin Maria; Ülavere, Eero; Tammoja, Heiki; Valtin, Juhan 14th International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of energy and geotechnology. II" : Pärnu, Estonia, January 13-18, 2014 2014 / p. 112-117 : ill

AdAM: adaptive fault-tolerant approximate multiplier for edge DNN accelerators

Taheri, Mahdi; Cherezova, Natalia; Nazari, Samira; **Rafiq, Ahsan; Azarpeyvand, Ali; Ghasempouri, Tara; Daneshtalab, Masoud; Raik, Jaan; Jenihhin, Maksim** 2024 IEEE European Test Symposium (ETS): ETS 2024 : May 20-24, 2024, The Hague, Netherlands : proceedings 2024 <https://doi.org/10.1109/ETS61313.2024.10567161> [Conference Proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Adaptive Kalman filter based data aggregation in fault-resilient Underwater Sensor Networks

Vihman, Lauri; Raik, Jaan 2023 24th International Conference on Digital Signal Processing (DSP) 2023 / p. 1-5 <https://doi.org/10.1109/DSP58604.2023.10167982>

Adjusted electrical equivalent circuit model of induction motor with broken rotor bars

Rassõlkin, Anton; Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants; Petrov, Aleksei; Plokhov, Igor; Kotelnikov, Aleksandr PQ2016 : the 10th International Conference 2016 Electric Power Quality and Supply Reliability Conference (PQ) : August 29-31, 2016, Tallinn, Estonia : proceedings 2016 / p. 213-218 : ill <https://doi.org/10.1109/PQ.2016.7724115>

Adjusted electrical equivalent circuit model of induction motor with broken rotor bars and eccentricity faults

Petrov, Aleksei; Plokhov, Igor; **Rassõlkin, Anton; Vaimann, Toomas; Kallaste, Ants; Belahcen, Anouar** Proceeding of the 2017 IEEE 11th International Symposium on Diagnostics for Electric Machines, Power Electronics and Drives (SDEMPED) : [Tinos (Greece), August 29 - September 01, 2017] 2017 / p. 58-64 : ill <https://doi.org/10.1109/DEMPED.2017.8062334>

An advanced diagnostic approach for broken rotor bar detection and classification in DTC controlled induction motors by leveraging dynamic SHAP interaction feature selection (DSHAP-IFS) GBDT methodology

Khan, Muhammad Amir; Asad, Bilal; Vaimann, Toomas; Kallaste, Ants Machines 2024 / art. 495 <https://doi.org/10.3390/machines12070495> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Advances in machine fault diagnosis

Vaimann, Toomas Applied sciences 2021 / art. 7348, 5 p <https://doi.org/10.3390/app11167348> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Advances in machine fault diagnosis

2022 <https://doi.org/10.3390/books978-3-0365-5110-4>

Advances in machine fault diagnosis

Vaimann, Toomas Advances in machine fault diagnosis 2022 / p. 1-5 <https://doi.org/10.3390/app11167348>

Air-core sensors operation modes for partial discharge detection and on-line diagnostics in medium voltage networks

Kütt, Lauri; Shafiq, Muhammad; **Mölder, Heigo; Järvik, Jaan;** Lehtonen, Matti Scientific Journal of Riga Technical University. Electrical, control and communication engineering 2013 / p. 5-12 : ill

Algorithms for hierarchical fault simulation in digital systems

Ubar, Raimund-Johannes; Raik, Jaan; Klüver, B. Proceedings of the 10th International Conference : Mixed Design of Integrated Circuits and Systems : MIXDES 2003 : Lodz, Poland, 26-28 June 2003 2003 / p. 530-535 : ill

Analysis and improvement of resilience for long short-term memory neural networks

Ahmadilivani, Mohammad Hasan; Raik, Jaan; Daneshtalab, Masoud; Kuusik, Alar 2023 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT) 2023 / 4 p <https://doi.org/10.1109/DFT59622.2023.10313559>

Analysis of common mode and rapidly varying voltage profile on stator current harmonics of an inverter-fed induction motor

Sardar, Muhammad Usman; Vaimann, Toomas; Kütt, Lauri; Kallaste, Ants; Asad, Bilal; Kudelina, Karolina; Akbar, Siddique 2023 IEEE 64th International Scientific Conference on Power and Electrical Engineering of Riga Technical University (RTUCON), Riga, Latvia, October 9-10, 2023 : conference proceedings 2023 / 6 p. : ill <https://doi.org/10.1109/RTUCON60080.2023.10413067>

Analysis of grain orientation and defects in Sb₂Se₃ solar cells fabricated by close-spaced sublimation

Krautmann, Robert; Spalatu, Nicolae; Gunder, Rene; Abou-Ras, Daniel; Unold, Thomas; Schorr, Susan; **Oja Acik, Ilona; Krunks, Malle** GSFMT Scientific Conference 2021 : Tartu, June 14-15, 2021 : abstracts 2021 / P 17 https://fntdk.ut.ee/wp-content/uploads/2021/06/GSFMT_abstractbook_2021.pdf

Analysis of grain orientation and defects in Sb₂Se₃ solar cells fabricated by close-spaced sublimation : [journal article]

Krautmann, Robert; Spalatu, Nicolae; Gunder, Rene; Abou-Ras, Daniel; Unold, Thomas; Schorr, Susan; **Krunks, Malle; Oja Acik, Ilona** Solar energy 2021 / p. 494-500 <https://doi.org/10.1016/j.solener.2021.07.022> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Analysis of the vibration magnitude of an induction motor with different numbers of broken bars

Martinez, Javier; **Belahcen, Anouar;** Muetze, Annette IEEE transactions on industry applications 2017 / p. 2711-2720 : ill <https://doi.org/10.1109/TIA.2017.2657478> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

An analytic model for fault diagnosis in power distribution systems considering unreliable alarms

Wang, Chongyu; Pang, Kaiyuan; Zhang, Yong; **Wen, Fushuan; Palu, Ivo;** Xiong, Wen; Chen, Minghui; Shang, Huiyu 2020 IEEE Power & Energy Society General Meeting (GM 2020) 2020 / 5 I <https://doi.org/10.1109/PESGM41954.2020.9281468>

Anomaly detection and classification in power system state estimation: Combining model-based and data-driven methods

Asefi, Sajjad; Mitrovic, Mile; Cetenovic, Dragan; Levi, Victor; Gryazina, Elena; Terzija, Vladimir Sustainable energy, grids and networks 2023 / art. 101116, 14 p. : ill <https://doi.org/10.1016/j.segan.2023.101116> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Assessment and Enhancement of Hardware Reliability for Deep Neural Networks = Riistvara töökindluse hindamine ja täiustamine süvanärvivõrkude jaoks

Ahmadilivani, Mohammad Hasan 2025 https://www.ester.ee/record=b5739227*est <https://digikogu.taltech.ee/et/Item/652d50e3-773f-4de5-897d-86531feb0d56> <https://doi.org/10.23658/taltech.19/2025>

Assessment of diagnostic test for automated bug localization

Tihhomirov, Valentin; Tšepurov, Anton; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [6] p. : ill

Assessment of electricity supply interruption costs under restricted time and information resources

Raesaar, Peeter; Tiigimägi, Eeli; Valtin, Juhan Proceedings of the 2006 IASME/WSEAS International Conference on Energy & Environmental Systems : Chalkida, Greece, May 8-10, 2006 2006 / p. 409-415 : ill

Asynchronous fault detection in IEEE P1687 instrument network

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur IEEE 23rd North Atlantic Test Workshop : 14-16 May 2014, Binghampton, New York : proceedings 2014 / p. 73-78 : ill

At-speed on-chip diagnosis of board-level interconnect faults

Jutman, Artur Ninth IEEE European Test Symposium : ETS 2004 : 23-26 May 2004, Corsica, France : proceedings 2004 / p. 2-7 : ill https://www.researchgate.net/publication/4098807_At-speed_on-chip_diagnosis_of_board-level_interconnect_faults

Automated area and coverage optimization of minimal latency checkers

Azad, Siavoosh Payandeh; Niazmand, Behrad; Apneet Kaur; Raik, Jaan; Jervan, Gert; Hollstein, Thomas 2017 22nd IEEE European Test Symposium (ETS 2017), Limassol, Cyprus, 22 – 26 May 2017 : proceedings 2017 / p. 7-8 : ill <https://doi.org/10.1109/ETS.2017.7968211>

Automated identification of application-dependent safe faults in automotive systems-on-a-chips

Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sonza Reorda, Matteo; Hamdioui, Said; **Jenihhin, Maksim;** Sauer, Christian Electronics 2022 / art. 319 <https://doi.org/10.3390/electronics11030319> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Automated minimization of concurrent online checkers for network-on-chips

Saltarelli, Pietro; Niazmand, Behrad; Hariharan, Ranganathan; Raik, Jaan; Jervan, Gert; Hollstein, Thomas 10th International Symposium on Reconfigurable and Communication-centric Systems-on-Chip (ReCoSoC 2015) : Bremen, 29 June - 1 July 2015 2015 / [8] p. : ill <http://dx.doi.org/10.1109/ReCoSoC.2015.7238079>

Automated test bench generation for high-level synthesis flow ABELITE

Viilukas, Taavi; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes; Baranov, Samary Proceedings of IEEE East-West Design & Test Symposium (EWDTS'2011) : Sevastopol, Ukraine, September 9-12, 2011 / p. 13-16 : ill <https://ieeexplore.ieee.org/document/6116601>

Auvere jaama ehitaja on Enefit Powerile maksnud trahvi juba 130 miljonit

Nikolajev, Jüri err.ee 2022 [Auvere jaama ehitaja on Enefit Powerile maksnud trahvi juba 130 miljonit](#)

AWAIT : an ultra-lightweight soft-error mitigation mechanism for network-on-chip links

Janson, Karl; Pihlak, Rene; Azad, Siavoosh Payandeh; Niazmand, Behrad; Jervan, Gert; Raik, Jaan 2018 13th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC), Lille, France, July 9th-11th, 2018 / p. 1-6 : ill <https://doi.org/10.1109/ReCoSoC.2018.8449374>

BASTION - board and SoC test instrumentation for Ageing and No Failure Found

Devadze, Sergei MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 77

BASTION : board and SoC test instrumentation for ageing and no failure found

Jutman, Artur; Lotz, Christophe; Larsson, Erik; Sonza Reorda, Matteo; **Jenihhin, Maksim; Raik, Jaan** Proceedings of the 2017 Design, Automation & Test in Europe (DATE) : 27-31 March 2017, Swisstech, Lausanne, Switzerland 2017 / p. 115-120 : ill <https://doi.org/10.23919/DATE.2017.7926968>

Bearing fault analysis of BLDC motor intended for electric scooter application

Kudelina, Karolina; Asad, Bilal; Vaimann, Toomas; Rassõlkin, Anton; Kallaste, Ants 2021 IEEE 13th International Symposium on Diagnostics for Electrical Machines, Power Electronics and Drives (SDEMPED) 2021 / p. 427-432 <https://doi.org/10.1109/SDEMPED51010.2021.9605519>

The bearing faults detection methods for electrical machines — the state of the art

Khan, Muhammad Amir; **Asad, Bilal; Kudelina, Karolina; Vaimann, Toomas; Kallaste, Ants** Energies 2023 / art. 296 <https://doi.org/10.3390/en16010296> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Behavior modeling of faulty complex VLSIs : why and how?

Leveugle, R. BEC'98 : the 6th Biennial Conference on Electronics and Microsystems Technology, October 7-9, 1998, Tallinn, Estonia : proceedings 1998 / p. 191-194: ill

Bidirectional DC circuit breaker with improved performance during commissioning and reclosing

Pogulaguntla, Aditya; Raghavendra I, Venkata; Banavath, Satish Naik; **Chub, Andrii;** Sreekanth, Thamballa; Krishnamoorthy, Harish Sarma 24th European Conference on Power Electronics and Applications (EPE'22 ECCE Europe) 2022 / p. P1-P9 <https://ieeexplore.ieee.org/document/9907667>

Broken rotor bar fault detection of the grid and inverter-fed induction motor by effective attenuation of the fundamental component

Asad, Bilal; Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants; Rassõlkin, Anton; Iqbal, Muhammad Naveed IET electric power applications 2019 / p. 2005–2014 <https://doi.org/10.1049/iet-epa.2019.0350> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Broken rotor bar fault diagnostic of inverter fed induction motor using FFT, Hilbert and Park's vector approach

Asad, Bilal; Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants 2018 XIII International Conference on Electrical Machines (ICEM 2018) : Alexandroupoli, Greece, 3-6 September 2018 / p. 2352-2358 : ill <https://doi.org/10.1109/ICELMACH.2018.8506957>

Cable diagnostics methods for determining degradation caused by renewable energy production

Kiitam, Ivar; Taklaja, Paul; Niitsoo, Jaan; Hyonen, Petri 2015 IEEE 5th International Conference on Power Engineering, Energy and Electrical Drives (POWERENG) : proceedings : May 11-13, 2015, Riga, Latvia 2015 / p. 220-224 : ill

Calculation of probabilistic testability measures for digital circuits with Structurally Synthesized BDDs

Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan Microprocessors and microsystems 2020 / art. 103117, 12 p <https://doi.org/10.1016/j.micpro.2020.103117> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Calculation of the diagnosibility of digital circuits without using fault models

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 159-162 : ill

Capacitor coupled voltage transformer inaccuracy effect on circuit breaker operation

Asefi, Sajjad; Andreesen, Guido; Kilter, Jako; Landsberg, Mart 2023 23rd International Scientific Conference on Electric Power Engineering (EPE) 2023 / 5 p <https://doi.org/10.1109/EPE58302.2023.10149279>

Causes of indefinite faults in Estonian 110 kV overhead power grid

Taklaja, Paul; Oidram, Rein; Niitsoo, Jaan; Palu, Ivo Oil shale 2013 / p. 225-243 : ill https://artiklid.elnet.ee/record=b2631741*est

Changing of magnetic flux density distribution in a squirrel-cage induction motor with broken rotor bars

Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants Elektronika ir elektrotehnika = Electronics and electrical engineering 2014 / p. 11-14 : ill <https://doi.org/10.5755/j01.eee.20.7.8018> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Combinational fault simulation in sequential circuits

Ubar, Raimund-Johannes; Kõusaar, Jaak; Gorev, Maksim; Devadze, Sergei 2015 IEEE International Symposium on Circuits and Systems : 24-27 May 2015, Lisboa, Portugal : [proceedings] 2015 / p. 2876-2879 : ill <https://doi.org/10.1109/ISCAS.2015.7169287> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Combined fault-model free cause-effect and effect-cause fault diagnosis in block-level digital networks

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan ASQED'09 : 1st Asia Symposium on Quality Electronic Design : Kuala Lumpur, Malaysia, July 15-16, 2009 2009 / p. 385-390 <https://ieeexplore.ieee.org/document/5206232>

Combined FE and two dimensional spectral analysis of broken cage faults in induction motors

Martinez, Javier; **Belahcen, Anouar**; Arkkio, Antero Proceedings : IECON 2013 - 39th Annual Conference of the IEEE Industrial Electronics Society : Vienna, Austria, 10-14 November, 2013 2013 / p. 2674-2679 : ill <https://ieeexplore.ieee.org/document/6699553>

Combined pseudo-exhaustive and deterministic testing of array multipliers

Oyeniran, Adeboye Stephen; Azad, Siavoosh Payandeh; Ubar, Raimund-Johannes 2018 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 21st edition, 24th-26th May, Cluj-Napoca, Romania : proceedings 2018 / 6 p. : ill <https://doi.org/10.1109/AQTR.2018.8402708>

Combining fault analysis technologies for ISO26262 functional safety verification

Augusto da Silva, Felipe; **Bagbaba, Ahmet Cagri**; Hamdioui, Said; Sauer, Christian 2019 IEEE 28th Asian Test Symposium (ATS) : 10-13 December 2019, Kolkata, India : proceedings 2019 / p. 129-134 : ill <https://doi.org/10.1109/ATS47505.2019.00024>

Common-ground energy router structure with enhanced reliability and protection = Ühise nulljuhtmega suurendatud töökindluse ja kaitsega energiaruuter

Rahimpour, Saeed 2024 <https://doi.org/10.23658/taltech.45/2024> https://www.ester.ee/record=b5694226*est <https://digikogu.taltech.ee/et/Item/520b18fc-f0a8-4a08-ade8-d3b890d253ff>

Complex delay fault reasoning with sequential 7-valued algebra

Kõusaar, Jaak; Ubar, Raimund-Johannes; Alekseev, Igor 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2015.7102403>

Comprehensive Diagnostic Assessment of Inverter Failures in a Utility-Scale Solar Power Plant : A Case Study Based on Field and Laboratory Validation

Kull, Karl; **Asad, Bilal; Naseer, Muhammad Usman; Kallaste, Ants; Vaimann, Toomas** Sensors 2025 / art. 3717 <https://doi.org/10.3390/s25123717>

A Comprehensive Study of Partial Discharge Based Extrinsic Aging in Nomex Insulation Films : Modeling, Simulation and Measurement

Choudhary, Maninder; Shafiq, Muhammad; Bhattarai, Abhinav; **Kiitam, Ivar; Taklaja, Paul; Palu, Ivo** Electric Power Systems Research 2025 / art. 111663 <https://doi.org/10.1016/j.epsr.2025.111663>

Condition monitoring and fault detection for electrical machines using IOT

Raja, Hadi Ashraf; Vaimann, Toomas; Rassõlkin, Anton; Kallaste, Ants Proceedings of the Future Technologies Conference (FTC) 2022. Volume 2 2023 / p. 162-173 https://doi.org/10.1007/978-3-031-18458-1_12 [Conference proceedings at Scopus](#) [Article at Scopus](#)

Condition monitoring of electrical machines

Vaimann, Toomas; Kallaste, Ants 11th International Symposium "Topical Problems in the Field of Electrical and Power Engineering." Doctoral School of Energy and Geotechnology II : Pärnu, Estonia, January 16-21, 2012 2012 / p. 209-212 : ill

Condition monitoring of electrical machines and its relation to industrial internet

Belahcen, Anouar; Gyftakis, Konstantinos N.; Martinez, Javier; Climente-Alarcon, Vicente; **Vaimann, Toomas** 2015 IEEE Workshop on Electrical Machines Design, Control and Diagnosis (WEMDCD) : proceedings : Castello del Valentino, Torino, Italy, 26-27 March, 2015 2015 / p. 233-241 : ill <http://dx.doi.org/10.1109/WEMDCD.2015.7194535>

Conditional fault collapsing in digital circuits with shared structurally synthesized BDDs [Online resource]

Jürimägi, Lembit; Ubar, Raimund-Johannes BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings

Construction of the tests of combinational circuit failures by analyzing the orthogonal disjunctive normal forms represented by the alternative graphs

Matrosova, A.Yu.; Pleshkov, A.G.; **Ubar, Raimund-Johannes** Automation and remote control 2005 / p. 313-327 : ill <https://doi.org/10.1007/s10513-005-0054-9>

Cost-effective concurrent hardware checkers for network on chip based system on chip = Kulutõhusad süsteemiga paralleelsed rikkemonitorid kiipvõrkudel põhinevatele kiipsüsteemidele

Hariharan, Ranganathan 2019 <https://digi.lib.ttu.ee/i/?12854> https://www.ester.ee/record=b5243161*est

Cost-efficient real-time condition monitoring and fault diagnostics system for BLDC motor using IoT and Machine learning

Raja, Hadi Ashraf; Raval, Hardik; Vaimann, Toomas; Kallaste, Ants; Rassõlkin, Anton; Belahcen, Anouar Diagnostika '22 : 2022 International Conference on Diagnostics in Electrical Engineering : conference proceedings 2022 / 4 p. <https://doi.org/10.1109/Diagnostika55131.2022.9905102>

Critical path tracing based simulation of transition delay faults

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan 2014 17th Euromicro Conference on Digital System Design : DSD 2014 : 27-29 August 2014, Verona, Italy : proceedings 2014 / p. 108-113 : ill

Critical path tracing based simulation of transition delay faults

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 61-66 : ill

Cross-layer dependability management in network on chip based system on chip = Kiipvõrkudel põhinevate süsteemide kihtideülene usaldatavuse haldus

Azad, Siavoosh Payandeh 2018 <https://digi.lib.ttu.ee/i/?9948> https://www.ester.ee/record=b5056143*est

Data-driven cross-layer fault management architecture for sensor networks

Vihman, Lauri; Kruusmaa, Maarja; Raik, Jaan 16th European Dependable Computing Conference : EDCC 2020 : Virtual Conference, Munich, Germany, 7-10 September 2020 : proceedings 2020 / art. 20094188, p. 33-40 <https://doi.org/10.1109/EDCC51268.2020.00015>

Data-driven fault-resilient cross-layer sensor network architecture = Andmepõhine tõrkekindel kihtideülene sensorvõrgu arhitektuur

Vihman, Lauri 2024 https://www.ester.ee/record=b5657135*est <https://digikogu.taltech.ee/et/Item/00a93258-dc0f-4a4d-822f-099fff757224> <https://doi.org/10.23658/taltech.7/2024>

DECIDER : a decision diagram based hierarchical test generation system

Jervan, Gert; Markus, Antti; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the 2nd International Workshop on Design and Diagnostics of Electronic Circuits and Systems, Szczyrk, Poland, September 2-4, 1998 1998 / p. 269-273 <https://www.ida.liu.se/labs/eslab/publications/pap/db/DDECS98.pdf>

Deductive fault simulation on structurally synthesized BDDs

Aarna, Margit; Ubar, Raimund-Johannes; Raik, Jaan BEC 2004 : Baltic Electronics Conference : Post-Graduate Student Session : Tallinn University of Technology, October 3-6, 2004, Tallinn, Estonia 2004 / p. 11 : ill

DeepAxe : a framework for exploration of approximation and reliability trade-offs in DNN accelerators

Taheri, Mahdi; Riazati, Mohamad; Ahmadilivani, Mohammad Hasan; Jenihhin, Maksim; Daneshtalab, Masoud; Raik, Jaan; Sjödin, Mikael; Lisper, Björn 2023 24th International Symposium on Quality Electronic Design (ISQED) 2023 / 8 p. : ill <https://doi.org/10.1109/ISQED57927.2023.10129353>

DeepVigor: Vulnerability Value RanGes and FactORs for DNNs' Reliability Assessment

Ahmadilivani, Mohammad Hasan; Taheri, Mahdi; Raik, Jaan; Daneshtalab, Masoud; Jenihhin, Maksim IEEE European Test Symposium (ETS) : Venice, Italy, 22-26 May 2023 : proceedings 2023 / 6 p. : ill <https://doi.org/10.1109/ETS56758.2023.10174133>

DeepVigor+: Scalable and Accurate Semi-Analytical Fault Resilience Analysis for Deep Neural Networks

Ahmadilivani, Mohammad Hasan; Raik, Jaan; Daneshtalab, Masoud; Jenihhin, Maksim arXiv.org 2024 / 14 p. : ill <https://doi.org/10.48550/arXiv.2410.15742>

Defect oriented fault coverage of 100stuck-at fault test sets

Blyzniuk, M.; Cibakova, Tatiana; Gramatova, Elena; Kuzmicz, W.; Lobur, M.; Pleskacz, Witold A.; Raik, Jaan; Ubar, Raimund-Johannes Proceedings of the 7th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2000 : Gdynia, Poland, 15-17 June 2000 2000 / p. 511-516 : ill <https://repo.pw.edu.pl/info/seam?ps=20&id=WUT7e20f35d67ae45d3b2d1264d7a4ba722&en&pn=1&cid=156607>

Defect-oriented fault simulation and test generation in digital circuits

Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE ISQED 2001 : proceedings of the IEEE 2001 2nd International Symposium on Quality Electronic Design : March 26-28, 2001, San Jose, California 2001 / p. 365-371
<https://ieeexplore.ieee.org/document/915257>

Defect-oriented library builder and hierarchical test generation

Cibakova, Tatiana; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 163-168 : ill

Defect-oriented mixed-level fault simulation in digital systems

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina Facta Universitatis [Niš]. Series electronics and energetics 2002 / 1, April, p. 123-136 : ill

Defect-oriented modul-level fault diagnosis in digital circuits

Kostin, Sergei; Ubar, Raimund-Johannes; Raik, Jaan Proceedings of the 2011 IEEE Symposium on Design and Diagnostics of Electronic Circuits and Systems : April 13-15, 2011, Gottbus, Germany 2011 / p. 81-86

Defect-oriented test generation and fault simulation in the environment of MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Gramatova, Elena; Fisherova, Maria; **Ivask, Eero; Ubar, Raimund-Johannes**; Pleskacz, Witold A.; Kuzmicz, W. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 303-306 : ill

Defect-oriented test generation using probabilistic estimation

Cibakova, Tatiana; Fischerova, Maria; Gramatova, Elena; Kuzmicz, W.; Pleskacz, Witold A.; **Raik, Jaan; Ubar, Raimund-Johannes** Proceedings of the 8th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2001 : Zakopane, Poland, 21-23 June 2000 2001 / p. 131-136 : ill

Defektide ja rikete seoste analüüs : lepingu Lep16039 aruanne [Võrguväljaanne]

Palu, Ivo; Keel, Matti; Tammoja, Heiki 2016 https://www.elektrilevi.ee/-/doc/6305157/ettevottest/defektide_rikete_aruanne.pdf

DefSim - the defective IC

Pleskacz, Witold A.; **Jutman, Artur; Ubar, Raimund-Johannes; Devadze, Sergei** DATE 2007 : Design Automation and Test in Europe : Nice, France, April 16-20, 2007 2007 / p. s96 (2 p.)

Delay fault investigation at the register transfer level

Fischerova, Maria; Gramatova, Elena BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 141-144

Dependability improvements of NoC-based systems = Töökindluse parandamine kiipvõrkudel põhinevates süsteemides

Niazmand, Behrad 2018 <https://digi.lib.ttu.ee/i/?9879> https://www.ester.ee/record=b4907650*est

Dependence of the carrier removal rate in 4H-SiC PN structures on irradiation temperature

Lebedev, Alexander A.; Davydovskaya, Klavdia S.; Kozlovski, Vitali V.; **Korolkov, Oleg; Sleptsuk, Natalja; Toompuu, Jana** Silicon Carbide and Related Materials 2018 : 12th European Conference on Silicon Carbide and Related Materials (ECSCRM 2018) : Selected, peer reviewed papers from the European Conference on Silicon Carbide and Related Materials (ECSCRM 2018), September 2-6, 2018, Birmingham, UK 2019 / p. 730-733 https://doi.org/10.4028/www.scientific.net/MSF.963.730_Conference_proceeding_at_Scopus [Article at Scopus](https://doi.org/10.4028/www.scientific.net/MSF.963.730_Conference_proceeding_at_Scopus)

Design error diagnosis in digital circuits with stuck-at fault model

Jutman, Artur; Ubar, Raimund-Johannes Microelectronics reliability 2000 / p. 307-320 : ill [https://doi.org/10.1016/S0026-2714\(99\)00203-6](https://doi.org/10.1016/S0026-2714(99)00203-6)

Design error diagnosis in digital circuits without error model

Ubar, Raimund-Johannes; Borriane, Dominique VLSI : systems on a chip : IFIP TC10 WG10.5 Tenth International Conference on Very Large Scale Integration (VLSI'99) : December 1-4, 1999, Lisboa, Portugal 1999 / p. 281-292 : ill
https://www.researchgate.net/publication/292157544_Design_Error_Diagnosis_in_Digital_Circuits_without_Error_Model

Design error diagnosis in scan-path designs

Ubar, Raimund-Johannes 2nd IEEE Latin American Test Workshop : LATW 2001 : Cancun, Mexico, February 11-14, 2001 : digest of papers 2001 / p. 162-168 : ill

Design error diagnosis with re-synthesis in combinational circuits

Ubar, Raimund-Johannes Journal of electronic testing : theory and applications 2003 / 1, p. 73-82 : ill
<https://link.springer.com/article/10.1023/A:1021948013402>

Design error localization in digital circuits by stuck-at fault test patterns

Jutman, Artur; Ubar, Raimund-Johannes [MIEL] 2000 : 22nd International Conference on Microelectronics : Niš, Yugoslavia, 14-17 May 2000 : proceedings. Volume 2 2000 / p. 723-726 <https://ieeexplore.ieee.org/document/838792>

Design issues of redundant protection and supervision system for the special purpose power converters [Electronic resource]

Vinnikov, Dmitri; Roasto, Indrek; Vodovozov, Valery International Conference on Renewable Energies and Power Quality : ICREPQ'09 : Valencia, Spain, 15th to 17th April 2009 2009 / [6] p. [CD-ROM] <https://www.icrepq.com/ICREPQ%2709/356-vinnikov.pdf>

Design technologies for system-on-chip : fault simulation in complex digital designs

Hahanov, V.; Ubar, Raimund-Johannes Автоматизированные системы управления и приборы автоматики, 2003 2003 / p. 16-35

Detection of induction motor broken bars in grid and frequency converter supply

Vaimann, Toomas; Belahcen, Anouar; Martinez, Javier; Kilk, Aleksander Przegląd elektrotechniczny 2014 / p. 90-94 : ill <https://www.pe.org.pl/articles/2014/1/22.pdf> [Journal metrics at Scopus](#) [Article at Scopus](#)

Determination of the nonfaulty limits of circuit characteristics in the fault identification of discrete-type circuits

Gadzheva, Elissaveta BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 97-100: ill

Determined-safe faults identification : a step towards ISO26262 hardware compliant designs

Augusto da Silva, Felipe; Bagbaba, Ahmet Cagri; Sartoni, Sandro; Cantoro, Riccardo; Sonza Reorda, Matteo; Hamdioui, Said; Sauer, Christian 2020 25th IEEE European Test Symposium (ETS) 2020 / 6 p. : ill <https://doi.org/10.1109/ETS48528.2020.9131568>

Determining the unknown faults of the HV overhead lines

Taklaja, Paul; Niitsoo, Jaan; Palu, Ivo Proceedings of the 13th International Scientific Conference Electric Power Engineering 2012 : EPE 2012 : Brno. Vol. 1 2012 / p. 187-192 : ill

Development of a Substation Risk-Based Asset Management Decision-Making Process in the Case of Insufficient Information = Alajaama riskipõhise varahalduse otsustusprotsessi arendamine ebapiisava sisendteabe tingimustes

Andresen, Guido 2025 https://www.ester.ee/record=b5754736*est <https://digikogu.taltech.ee/et/Item/49e349b9-c62b-4a9e-af14-5c8408e54028> <https://doi.org/10.23658/taltech.52/2025>

A DFT scheme to improve coverage of hard-to-detect faults in FinFET SRAMs

Cardoso Medeiros, Guilherme; Gürsoy, Cemil Cem; Fieback, Moritz; Wu, Lizhou; Jenihhin, Maksim; Taouil, Mottaqiallah; Hamdioui, Said 2020 Design, Automation & Test in Europe Conference & Exhibition (DATE), 9-13 March 2020, Grenoble, France : proceedings 2020 / p. 792-797 <https://doi.org/10.23919/DATE48585.2020.9116278>

DFT-based external test and diagnosis of mesh-like networks on chips = Testitavusel põhinev välise testi ja diagnoosi meetod kahemõõtmelistele kiipvõrkudele

Govind, Vineeth 2009 <https://digi.lib.ttu.ee/1/7454> https://www.ester.ee/record=b2539211*est

Diagnostic modeling of digital systems with low- and high-level decision diagrams

Ubar, Raimund-Johannes LATW2013 : 14th IEEE Latin-American Test Workshop, Cordoba, Argentina, April 3-5, 2013 : [proceedings] 2013 / [1] p

Diagnostic modeling of digital systems with multi-level decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Jutman, Artur; Jenihhin, Maksim Design and test technology for dependable systems-on-chip 2011 / p. 92-118 : ill https://www.researchgate.net/publication/344994231_Diagnostic_Modeling_of_Digital_Systems_with_Multi-Level_Decision_Diagrams

Diagnostic software

Ubar, Raimund-Johannes Concise encyclopedia of software engineering 1993 / p. 101-105

Diagnostics of induction motor rotor faults using analysis of stator current

Vaimann, Toomas 6th International Symposium "Topical Problems in the Field of Electrical and Power Engineering" : Doctoral School of Energy and Geotechnology : [Kuressaare, January 12-17, 2009] 2009 / p. 13-17 : ill

DIAGNOZER : a laboratory tool for teaching research in diagnosis of electronic systems [Electronic resource]

Ubar, Raimund-Johannes; Kostin, Sergei; Jutman, Artur; Raik, Jaan; Wuttke, Heinz-Dietrich 2009 IEEE International Conference on Microelectronic Systems Education MSE '09 : 25-27 July 2009, San Francisco, California : [proceedings] 2009 / p. 12-15 : ill. [CD-ROM] <http://dx.doi.org/10.1109/MSE.2009.5270842>

Digital logic simulation with compressed BDDs

Ubar, Raimund-Johannes; Mironov, Dmitri; Devadze, Sergei; Raik, Jaan Proceedings : 2011 IEEE International Conference on

Digital twin service unit development for an EV induction motor fault detection

Rjabtšikov, Viktor; Mohamed, Mahmoud Ibrahim Hassanin; Asad, Bilal; Rassõlkin, Anton; Vaimann, Toomas; Kallaste, Ants; Kuts, Vladimir; Stepień, Mariusz; Krawczyk, Mateusz 2023 IEEE International Conference on Electric Machines and Drives (IEMDC) 2023 / 5 p <https://doi.org/10.1109/IEMDC55163.2023.10239085>

Digital Twin service unit for AC motor stator inter-turn short circuit fault detection

Rjabtšikov, Viktor; Rassõlkin, Anton; Asad, Bilal; Vaimann, Toomas; Kallaste, Ants; Kuts, Vladimir; Jegorov, Sergei; Stepień, Mariusz; Krawczyk, Mateusz 2021 28th International Workshop on Electric Drives : Improving Reliability of Electric Drives (IWED) 2021 <https://doi.org/10.1109/IWED52055.2021.9376328>

Directional calibration of rogowski coil for localization of partial discharges in smart distribution networks

Shafiq, Muhammad; Kütt, Lauri; Isa, M.; Hashmi, M.; Lehtonen, Matti International review of electrical engineering 2012 / p. 5881-5890
https://www.researchgate.net/publication/262703688_Directional_Calibration_of_Rogowski_Coil_for_Localization_of_Partial_Discharges_in_Smart_Distribution_Networks

Distance encoding waves for identification of lighting failures

Galkin, Ilja; Suzdalenko, Alexander; Armas, Jelena BEC 2012 : 2012 13th Biennial Baltic Electronics Conference : proceedings of the 13th Biennial Baltic Electronics Conference : October 3-5, 2012, Tallinn, Estonia 2012 / p. 227-230 : ill

Distributed approach for parallel exact critical path tracing fault simulation

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes MIXDES 2010 : 17th International Conference "Mixed Design of Integrated Circuits and Systems" : June 24-26, 2010, Wroclaw, Poland 2010 / p. 471-476 : ill

Distributed approach for parallel exact critical path tracing fault simulation

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes International journal of microelectronics and computer science 2010 / p. 165-174 : ill

Distributed fault simulation with collaborative load balancing for VLSI circuits

Ivask, Eero; Devadze, Sergei; Ubar, Raimund-Johannes Scalable computing : practice and experience 2011 / p. 153-163 : ill

Double phase fault collapsing with linear complexity in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Josifovska, Galina; Oyeniran, Adeboye Stephen DSD 2015 : 18th Euromicro Conference on Digital Systems Design : 26-28 August 2015, Funchal, Madeira, Portugal 2015 / p. 700-705 : ill

Dynamic analysis of digital circuits with 5-valued simulation

Ubar, Raimund-Johannes Mixed design of integrated circuits and systems 1998 / p. 187-192: ill
https://link.springer.com/chapter/10.1007/978-1-4615-5651-0_29

Eesti soosetete leviku seosed tektooniliste riketega

Štokalenko, Mihkel; Orru, Mall XIX aprillikonverentsi "Eesti mere- ja maapõue uuringutest ning arukast kasutamisest" teesid 2011 / lk. 25-27 : kaart

Effect of electrode shape on medium voltage covered conductor insulation durability under electric stress

Kiitam, Ivar; Taklaja, Paul; Tuttelberg, Kaur 59th Annual International Scientific Conference on Power and Electrical Engineering : November 12, 13, 2018, Riga Technical University (RTUCON) : conference proceedings 2018 / 6 p. : ill
<https://doi.org/10.1109/RTUCON.2018.8659862>

Effect of PM parameters variability on the operation quantities of a wind generator

Kallaste, Ants; Belahcen, Anouar; Vaimann, Toomas 2015 IEEE Workshop on Electrical Machines Design, Control and Diagnosis (WEMDCD) : proceedings : Castello del Valentino, Torino, Italy, 26-27 March, 2015 2015 / p. 242-247 : ill
<http://dx.doi.org/10.1109/WEMDCD.2015.7194536>

Effective scalable IEEE 1687 instrumentation network for fault management

Jutman, Artur; Shibin, Konstantin; Devadze, Sergei IEEE design & test 2013 / p. 26-35 : ill
<https://doi.org/10.1109/MDAT.2013.2278535> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Efficient fault injection based on dynamic HDL slicing technique

Bagbaba, Ahmet Cagri; Jenihhin, Maksim; Raik, Jaan; Sauer, Christian 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS 2019) : 1-3 July 2019, Greece 2019 / p. 52-53 : ill
<https://doi.org/10.1109/IOLTS.2019.8854419>

Efficient methodology for ISO26262 functional safety verification

Augusto da Silva, Felipe; Bagbaba, Ahmet Cagri; Hamdioui, Said; Sauer, Christian 2019 IEEE 25th International Symposium on

Efficient single-pattern fault simulation on structurally synthesized BDDs

Raik, Jaan; Ubar, Raimund-Johannes; Devadze, Sergei; Jutman, Artur Dependable Computing - EDCC-5 : 5th European Dependable Computing Conference : Budapest, Hungary, April 20-22, 2005 : proceedings 2005 / p. 332-344 : ill

EFIC-ME : a fast emulation based fault injection control and monitoring enhancement

Abideen, Zain Ul; Rashid, Muhammad Haroon IEEE Access 2020 / p. 207705-207716

<https://doi.org/10.1109/ACCESS.2020.3038198> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Eksperdid: päikesetormide mõju pärast tänapäeval enam muretsema ei pea

Piir, Rait novaator.err.ee 2024 [Eksperdid: päikesetormide mõju pärast tänapäeval enam muretsema ei pea](#)

Elektrilevi investeeringutest ja võrgu katkestustest

Rajangu, Väino Elektriala 2015 / lk. 28 https://artiklid.elnet.ee/record=b2738903*est

Elektrimasinate terviserikkeid aitaks ennetada tehisintellekt [Võrguväljaanne]

Kudelina, Karolina novaator.err.ee 2021 ["Elektrimasinate terviserikkeid aitaks ennetada tehisintellekt"](#)

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V : kaitstesüsteemide katsetus-, mõõte- ja seireseadmed. Osa 3, Rikkesilmuse näivtakistus = Electrical safety in low voltage distribution systems up to 1000 V a.c. and 1500 V d.c. : equipment for testing, measuring or monitoring of protective measures. Part 3, Loop impedance (IEC 61557-3:2019)

2022 https://www.ester.ee/record=b5509793*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V : kaitstesüsteemide katsetus-, mõõte- ja seireseadmed. Osa 7, Faasijärjestus = Electrical safety in low voltage distribution systems up to 1000 V a.c. and 1500 V d.c. : equipment for testing, measuring or monitoring of protective measures. Part 7, Phase sequence (IEC 61557-7:2019)

2022 https://www.ester.ee/record=b5509797*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitstesüsteemide katsetus-, mõõte- ja seireseadmed. Osa 10, Kombineeritud mõõteseadmed kaitseviiside katsetamiseks, mõõtmiseks ja seireks = Electrical safety in low voltage distribution systems up to 1000 V a.c. and 1500 V d.c. Equipment for testing, measuring or monitoring of protective measures. Part 10, Combined measuring equipment for testing, measuring or monitoring of protective measures (IEC 61557-10:2000)

2010 https://www.ester.ee/record=b2630134*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitstesüsteemide katsetus-, mõõte- ja seireseadmed

Risthein, Endel 2009 https://www.ester.ee/record=b2462029*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitstesüsteemide katsetus-, mõõte- ja seireseadmed

Risthein, Endel 2009 https://www.ester.ee/record=b2462036*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitstesüsteemide katsetus-, mõõte- ja seireseadmed

Risthein, Endel 2009 https://www.ester.ee/record=b2478889*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitstesüsteemide katsetus-, mõõte- ja seireseadmed

Risthein, Endel 2009 https://www.ester.ee/record=b2478886*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitstesüsteemide katsetus-, mõõte- ja seireseadmed

Risthein, Endel 2009 https://www.ester.ee/record=b2478887*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitstesüsteemide katsetus-, mõõte- ja seireseadmed

Risthein, Endel 2010 https://www.ester.ee/record=b2594967*est

Elektriohutus madalpingevõrkudes vahelduvpingega kuni 1000 V ja alalispingega kuni 1500 V. Kaitstesüsteemide katsetus-, mõõte- ja seireseadmed

Risthein, Endel 2010 https://www.ester.ee/record=b2594972*est

Enabling cross-layer reliability and functional safety assessment through ML-based compact models

Alexandrescu, Dan; **Balakrishnan, Aneesh**; Lange, Thomas; Glorieux, Maximilien Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 6 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159750>

Enhancing hierarchical ATPG with a functional fault model for multiplexers [Electronic resource]

Raik, Jaan; Ubar, Raimund-Johannes 7th IEEE Workshop on Design and Diagnostics of Electronic Circuits and Systems : April 18-21, 2004, Stará Lesná, Slovakia : proceedings 2004 / p. 219-222 : ill. [CD-ROM] <https://www.semanticscholar.org/paper/Enhancing-Hierarchical-Atpg-with-a-Functional-Fault-Raik-Ubar/b42e913ac070fd774df97bd644c4e6220704f8d4>

Enhancing transmission line reliability : an AI-driven approach to fault identification and classification

Shabbir, Noman; Kamran, Daniel; Raja, Hadi Ashraf Electronics 2024

Environment for fault simulation acceleration on FPGA

Ellervee, Peeter; Raik, Jaan; Tihomirov, Valentin BEC 2004 : proceedings of the 9th Biennial Baltic Electronics Conference : October 3-6, 2004, Tallinn, Estonia 2004 / p. 217-220 : ill

Environment for FPGA-based fault emulation

Ellervee, Peeter; Raik, Jaan; Tammemäe, Kalle; Ubar, Raimund-Johannes Proceedings of the Estonian Academy of Sciences. Engineering 2006 / 3-2, p. 323-335 : ill

Environment for the analysis of functional self-test quality in digital systems

Ubar, Raimund-Johannes; Kostin, Sergei; Kruus, Helena; Aarna, Margit; Devadze, Sergei Proceedings of the Estonian Academy of Sciences 2014 / p. 151-162 : ill https://artiklid.elnet.ee/record=b2673964*est <https://doi.org/10.3176/proc.2014.2.05> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Estimation of complex derivatives and application for fault diagnosis

Baraškova, Tatjana; Arjassov, Gennadi; Gornostajev, Dmitri Annals of DAAAM for 2012 & Proceedings of the 23rd International DAAAM Symposium : Intelligent Manufacturing & Automation 2012 / p. 0469-0472 : ill. [CD-ROM] https://www.daaam.info/Downloads/Pdfs/proceedings/proceedings_2012/109.pdf

Estimation of complex derivatives application for fault diagnosis

Baraškova, Tatjana; Pascault, D. 17th International conference on "Mathematical Modelling and Analysis" : June 6-9, 2012, Tallinn, Estonia : abstracts 2012 / p. 19

Evaluating architectural, redundancy, and implementation strategies for radiation hardening of FinFET integrated circuits

Pagliarini, Samuel Nascimento; Benites, Luis; Martins, Mayler; Rech, Paolo; Kastensmidt, Fernanda IEEE transactions on nuclear science 2021 / p. 1045-1053 <https://doi.org/10.1109/TNS.2021.3070643> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Exact parallel critical path fault tracing to speed-up fault simulation in sequential circuits

Kõusaar, Jaak; Ubar, Raimund-Johannes; Kostin, Sergei; Devadze, Sergei; Raik, Jaan International journal of microelectronics and computer science 2018 / p. 9-18 <https://ijmcs.dmc.pl/web/guest/vol.-9-no.-1> https://ijmcs.dmc.pl/documents/10630/345460/IJMCS_1_2018_2.pdf

Experimental performance validation of Z-source DC circuit breaker for high impedance faults

Pogulaguntla, Aditya; Naik Banavath, Satish; **Chub, Andrii; Vinnikov, Dmitri; Singh, Rajendra** 2024 IEEE Sixth International Conference on DC Microgrids (ICDCM) 2024 / 5 p <https://doi.org/10.1109/ICDCM60322.2024.10664702>

Experts: No need to worry about the impact of solar storms today

Piir, Rait news.err.ee 2024 [Experts: No need to worry about the impact of solar storms today](#)

Explainability and transparency of classifiers for air-handling unit faults using explainable artificial intelligence (XAI)

Meas, Molika; Machlev, Ram; Köse, Ahmet; Tepļakov, Aleksei; Loo, Lauri; Levron, Yoash; Petlenkov, Eduard; Belikov, Juri Sensors 2022 / art. 6338 : ill <https://doi.org/10.3390/s22176338> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Exploiting high-level descriptions for circuits fault tolerance assessments

Benso, A.; Prinetto, Paolo; Rebaudengo, M.; Sonza Reorda, Matteo; **Raik, Jaan; Ubar, Raimund-Johannes** 1997 IEEE International Symposium on Defect and Fault Tolerance in VLSI Systems, Paris, October 20-22, 1997 1997 / p. 212-216 <https://ieeexplore.ieee.org/document/628327>

Exploration of Activation Fault Reliability in Quantized Systolic Array-Based DNN Accelerators

Taheri, Mahdi; Cherezova, Natalia; Ansari, Mohammad Saeed; Jenihhin, Maksim; Mahani, Ali; Daneshtalab, Masoud; Raik,

Jaan Proceedings of the Twenty Fifth International Symposium on Quality Electronic Design : ISQED 2024 2024 / 8 p. : ill
<https://ieeexplore.ieee.org/stamp/stamp.jsp?arnumber=10528372> <https://doi.org/10.1109/ISQED60706.2024.10528372> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Exploring the limits of early predictive maintenance in wind turbines applying an anomaly detection technique

Jankauskas, Mindaugas; Serackis, Artūras; Šapurov, Martynas; Pomarnacki, Raimondas; Baskys, Algirdas; Hyunh, Van Khang; **Vaimann, Toomas**; Zakis, Janis Sensors 2023 / art. 5695 <https://doi.org/10.3390/s23125695> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Extended checkers for control part of routers in network-on-chips

Hariharan, Ranganathan; Niazmand, Behrad; Hollstein, Thomas; Raik, Jaan; Jervan, Gert MEDIAN 2015 : the 4th Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : March 13, 2015, Grenoble, France 2015 / p. 36-39 : ill

Facebooki katkestus mõjutas nii ettevõtete kui ka riikide toimepidevust [Võrguväljaanne]

Pärli, Merilin err.ee 2021 ["Facebooki katkestus mõjutas nii ettevõtete kui ka riikide toimepidevust"](#)

Facebooki, Instagrami ja Whatsappi tabas tohutu ülemaailmne rike [Võrguväljaanne]

ohtuleht.ee 2021 ["Facebooki, Instagrami ja Whatsappi tabas tohutu ülemaailmne rike"](#)

Failure consequence evaluation of uncontrollable district heating network

Mao, Ding; Wang, Peng; **Ju, Yuchen**; Ni, Long Sustainable cities and society 2022 / art. 103593, 16 p. : ill
<https://doi.org/10.1016/j.scs.2021.103593> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Failure mechanisms in oil-shale pillars

Pastarus, Jüri-Rivaldo Oil shale 1994 / 3, p. 251-257: ill https://kirj.ee/wp-content/plugins/kirj/pub/OS-3-1994-251-257_20230316182205.pdf

Fast extended test access via JTAG and FPGAs

Devadze, Sergei; Jutman, Artur; Aleksejev, Igor; Ubar, Raimund-Johannes International Test Conference 2009 : November 1 - November 6, 2009, Austin Convention Center, Austin, Texas USA : proceedings 2009 / p. 1-7 : ill
<http://dx.doi.org/10.1109/TEST.2009.5355668>

Fast fault simulation for extended class of faults in scan-path circuits

Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan; Jutman, Artur Proceedings : Fifth IEEE International Symposium on Electronic Design, Test and Applications : DELTA 2010 : 13-15 January 2010, Ho Chi Minh City, Vietnam 2010 / p. 14-19
<https://ieeexplore.ieee.org/document/5438717>

Fast identification of true critical paths in sequential circuits

Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan; Jürimägi, Lembit Microelectronics reliability 2018 / p. 252-261 : ill <https://doi.org/10.1016/j.microrel.2017.11.027> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Fast RTL fault simulation using decision diagrams and bitwise set operations

Reinsalu, Uljana; Raik, Jaan; Ubar, Raimund-Johannes; Ellervee, Peeter 2011 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT) : 3-5 October 2011, Vancouver, Canada 2011 / p. 164-170
<https://ieeexplore.ieee.org/document/6104440>

Fault aliasing of signature analyzers

Kemnitz, Günter; Kärger, Reinhard BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 339-346: ill

Fault analysis of manufacturing systems as additional constraint by simulation

Karaulova, Tatjana; Papstel, Jüri International journal of simulation modelling 2003 / 1/2, p. 5-13 : ill

Fault analysis of manufacturing systems as additional constraint by simulation

Karaulova, Tatjana; Papstel, Jüri DAAAM international scientific book 2003 2003 / p. 295-304 : ill

Fault collapsing with linear complexity in digital circuits

Ubar, Raimund-Johannes; Mironov, Dmitri; Raik, Jaan; Jutman, Artur Proceedings of 2010 IEEE International Symposium on Circuits and Systems (ISCAS 2010) : 30 May - 2 June 2010, Paris, France 2010 / p. 653-656 : ill
<https://ieeexplore.ieee.org/document/5537504>

Fault detecting accuracy of mechanical damages in rolling bearings

Kudelina, Karolina; Baraškova, Tatjana; Shirokova, Veroonika; Vaimann, Toomas; Rassõlkin, Anton Machines 2022 / art. 86
<https://doi.org/10.3390/machines10020086> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Fault detection and predictive maintenance of electrical machines : perspective chapter

Raja, Hadi Ashraf; Kudelina, Karolina; Asad, Bilal; Vaimann, Toomas New Trends in Electric Machines - Technology and Applications 2022 <https://doi.org/10.5772/intechopen.107167>

Fault detection and protection strategy for multi-terminal HVDC grids using wavelet analysis

Kaur, Jashandeep; Jayasooriya, Manilka; Iqbal, Muhammad Naveed; Daniel, Kamran; Shabbir, Noman; Peterson, Kristjan Energies 2025 / art. 1147 <https://doi.org/10.3390/en18051147>

Fault detection and protection system for the power converters with high-voltage IGBTs [Electronic resource]

Vinnikov, Dmitri; Roasto, Indrek; Lehtla, Tõnu ICECS 2008 : The 15th IEEE International Conference on Electronics, Circuits and Systems : August 31 - September 3, 2008, Malta 2008 / p. 922-925 : ill. [CD-ROM] <https://ieeexplore.ieee.org/document/4675005>

Fault diagnosis in integrated circuits with BIST

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan; Evertson, Teet; Lensen, Harri 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 604-610 : ill <http://dx.doi.org/10.1109/DSD.2007.4341530>

Fault diagnosis in VLSI devices

Ubar, Raimund-Johannes Proceedings of the Estonian Academy of Sciences. Engineering 1995 / 1, p. 51-67

Fault diagnosis of additional vibration in Cartesian robot

Autsoo, Siarhei 21st International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of energy and geotechnology. III" : Pärnu, Estonia, June 15-18, 2022 2022 / p. 21-22 : ill https://www.ester.ee/record=b5504019*est

Fault diagnosis system of Cartesian robot for various belt tension

Autsoo, Siarhei; Vaimann, Toomas; Rassõlkin, Anton; Kudelina, Karolina 2022 International Conference on Diagnostics in Electrical Engineering (Diagnostics) 2022 / 4 I <https://doi.org/10.1109/Diagnostics55131.2022.9905111>

Fault emulation on FPGA : a feasibility study

Ellervee, Peeter; Raik, Jaan; Tihomirov, Valentin IEEE NORCHIP 2003 : 21 Norchip Conference : Riga, Latvia, 10-11 November 2003 : proceedings 2003 / p. 92-95 : ill https://www.researchgate.net/publication/246171898_Fault_Emulation_on_FPGA_A_Feasibility_Study

Fault locating in unearthed MV networks based on analysis of wave transients

Järvi, Jaan; Panov, Valeri The 4th International Conference Electric Power Quality and Supply Reliability : August 29...31, 2004, Pedase, Estonia : proceedings 2004 / p. 163-168

Fault management instrumentation network based on IEEE P1687 IJTAG

Shibin, Konstantin; Jutman, Artur; Devadze, Sergei European Test Symposium (ETS), 2013, Avignon, France 2013

Fault management techniques to enhance the reliability of power electronic converters : an overview

Rahimpour, Saeed; Husev, Oleksandr; Vinnikov, Dmitri; Vosoughi Kurdkandi, Naser; Tarzamni, Hadi IEEE Access 2023 / p. 13432-13446 <https://doi.org/10.1109/ACCESS.2023.3242918> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Fault model and test synthesis for RISC-processors

Ubar, Raimund-Johannes; Markus, Antti; Jervan, Gert; Raik, Jaan BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 229-232: ill

Fault modeling and diagnosis in digital systems

Ubar, Raimund-Johannes CREDES Summer School : Dependable Systems Design : handouts 2011 / p. 91-106 : ill

Fault path detection using a spectral method

Porwik, Piotr BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 315-318: ill

Fault prediction in power network

Kangilaski, Taivo The 7th Biennial Conference on Electronics and Microsystem Technology "Baltic Electronics Conference" : BEC 2000 : October 8 - 11, 2000, Tallinn, Estonia : conference proceedings 2000 / p. 289-292

Fault simulation and analysis of high-voltage circuit breaker's spring charging mechanism using a universal motor model

Asad, Bilal; Vaimann, Toomas; Kallaste, Ants; Kilter, Jako; Sardar, Muhammad Usman 2024 IEEE 65th International Scientific Conference on Power and Electrical Engineering of Riga Technical University (RTUCON) 2024 / 5 p <https://doi.org/10.1109/RTUCON62997.2024.10830846>

Fault simulation of digital systems = Digitaalsüsteemide rikete simuleerimine

Devadze, Sergei 2009 <https://digi.lib.ttu.ee/i/?445> https://www.ester.ee/record=b2508727*est

Fault simulation with parallel critical path tracing for combinational circuits using structurally synthesized BDDs

Devadze, Sergei; Raik, Jaan; Jutman, Artur; Ubar, Raimund-Johannes 7th IEEE Latin American Test Workshop LATW'06 : Buenos Aires, Argentina, March 26th-29th, 2006 : proceedings 2006 / p. 97-102 : ill

Fault simulation with parallel exact critical path tracing in multiple core environment

Gorev, Maksim; Ubar, Raimund-Johannes; Devadze, Sergei 2015 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2015 / p. 1180-1185 : ill

Fault-aware performance assessment approach for embedded networks

Malburg, Jan; **Janson, Karl; Raik, Jaan**; Dannemann, Frank 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 4 p. : ill
<https://doi.org/10.1109/DDECS.2019.8724670>

Fault-resilient NoC router with transparent resource allocation

Putkaradze, Tsotne; Azad, Siavoosh Payandeh; Niazmand, Behrad; Raik, Jaan; Jervan, Gert 12th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC2017), July 12-14, 2017, Madrid, Spain : proceedings 2017 / 8 p. : ill <https://doi.org/10.1109/ReCoSoC.2017.8016161> <https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=8016161>

Faults and fault models for integrated circuits and systems [Electronic resource] : [slides]

Ubar, Raimund-Johannes Design and Test Technology for Dependable Hardware/Software Systems : DEDIS/DAAD Summer Academy : BTU Cottbus, Sept. 1st-12th, 2008 2008 / [64] p. : ill. [CD-ROM]

Fehler in Automaten

1989 http://www.ester.ee/record=b2015320*est

Fehlerbestimmung in kombinatorischen Scaltungen durch Lösung der Booleschen Differentialgleichungen

Ubar, Raimund-Johannes Nachrichtentechnik, Elektronik : technisch-wissenschaftliche Zeitschrift für die gesamte elektronische Nachrichtentechnik 1978 / p. 330-334 : ill https://www.ester.ee/record=b1550811*est

The FEM based modeling and corresponding test rig preparation for broken rotor bars analysis

Asad, Bilal; Eensalu, Lauri; Vaimann, Toomas; Kallaste, Ants; Rassõlkin, Anton; Belahcen, Anouar 2019 IEEE 60th International Scientific Conference on Power and Electrical Engineering of Riga Technical University (RTUCON), 7-9 October 2019 : conference proceedings 2019 / 9 p. : ill <https://doi.org/10.1109/RTUCON48111.2019.8982350>

Finite element analysis based technique implementation for fault diagnostic of electrical machines

Akbar, Siddique 22nd International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology III : Pärnu, Estonia, August 23-26, 2023 2023 / p. 103-104
https://www.ester.ee/record=b5570906*est

First results on load model estimation using digital fault recorder measurements

Leinakse, Madis; Sarnet, Tanel; Kangro, Triin; Kilter, Jako 16th International Symposium "Topical Problems in the Field of Electrical and Power Engineering. Doctoral School of Energy and Geotechnology III" : Pärnu, Estonia, January 16-21, 2017 2017 / p. 101-105 : ill http://www.ester.ee/record=b4650094*est

FPGA based fault emulation of synchronous sequential circuits

Ellervee, Peeter; Raik, Jaan; Tihomirov, Valentin; Ubar, Raimund-Johannes Proceedings [of] 22nd NORCHIP Conference : Oslo, Norway, 8-9 November 2004 2004 / p. 59-62 <https://ieeexplore.ieee.org/abstract/document/1423822>

FPGA-based fault emulation of synchronous sequential circuits

Ellervee, Peeter; Raik, Jaan; Tammemäe, Kalle; Ubar, Raimund-Johannes IET computers and digital techniques 2007 / 2, p. 70-76 : ill <https://ieeexplore.ieee.org/abstract/document/1423822>

A framework for combining concurrent checking and online embedded test for low-latency fault detection in NoC routers

Saltarelli, Pietro; Niazmand, Behrad; Raik, Jaan; Govind, Vineeth; Hollstein, Thomas; Jervan, Gert; Hariharan, Ranganathan NOCS '15 : International Symposium on Networks-on-Chip : Vancouver, BC, Canada, September 28-30, 2015 2015 / [8] p. : ill <http://dx.doi.org/10.1145/2786572.2788713>

From online fault detection to fault management in network-on-chips : a ground-up approach

Azad, Siavoosh Payandeh; Niazmand, Behrad; Janson, Karl; Nevin, George; Oyeniran, Adeboye Stephen; Putkaradze, Tsotne; Apneet Kaur; Raik, Jaan; Jervan, Gert; Ubar, Raimund-Johannes; Hollstein, Thomas Proceedings 2017 IEEE 20th International Symposium on Design and Diagnostics of Electronic Circuit & Systems (DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 48-53 : ill <https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=7934553>

Generation of tests for the localization of single gate design errors in combinational circuits using the stuck-at fault model

Ubar, Raimund-Johannes; Borriane, Dominique XI Brazilian Symposium on Integrated Circuit Design, September 30 - October 3,

1998, Rio de Janeiro, Brazil : proceedings 1998 / p. 51-54 <https://ieeexplore.ieee.org/document/715409>

Guardbands in random testing

Kemnitz, Günter BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 85-88: ill

Handling of SETs on NoC links by exploitation of inherent redundancy in circular input buffers [Online resource]

Janson, Karl; Pihlak, Rene; Azad, Siavoosh Payandeh; Niazmand, Behrad; Jervan, Gert; Raik, Jaan BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 2018 / 4 p.: ill <https://doi.org/10.1109/BEC.2018.8600989>

Harmonic spectrum analysis of induction motor with broken rotor bar fault

Asad, Bilal; Vaimann, Toomas; Kallaste, Ants; Belahcen, Anouar 59th Annual International Scientific Conference on Power and Electrical Engineering : November 12, 13, 2018, Riga Technical University (RTUCON) : conference proceedings 2018 / 7 p. : ill <https://doi.org/10.1109/RTUCON.2018.8659842>

Health management for self-aware SoCs based on IEEE 1687 infrastructure

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur; Grabmann, Martin; Pricken, Robin IEEE Design & Test 2017 / p. 27-35 : ill <https://doi.org/10.1109/MDAT.2017.2750902> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Hierarchical approaches to test generation and fault simulation

Ubar, Raimund-Johannes Radioelectronics and informatics 2003 / p. 204

Hierarchical calculation of malicious faults for evaluating the fault-tolerance

Ubar, Raimund-Johannes; Devadze, Sergei; Jenihhin, Maksim; Raik, Jaan; Jervan, Gert; Ellervee, Peeter Proceedings : Fourth IEEE International Symposium on Electronic Design, Test and Applications : [DELTA 2008] : 23-25 January 2008, Hong Kong, SAR, China 2008 / p. 222-227 : ill <https://ieeexplore.ieee.org/document/4459544>

Hierarchical design error diagnosis in combinational circuits by stuck-at fault test patterns

Ubar, Raimund-Johannes; Jutman, Artur Proceedings of the 6th International Conference on Mixed Design of Integrated Circuits and Systems : MIXDES'99 : Krakow, Poland, 17-19 June 1999 1999 / p. 437-442 : ill <https://www.sciencedirect.com/science/article/pii/S0026271499002036>

Hierarchical fault diagnosis in embedded digital systems with multi-level decision diagrams [Electronic resource]

Ubar, Raimund-Johannes; Evertson, Teet; Lensen, Harri; Aarna, Margit 5th International Conference on Industrial Automation = Cinquieme Conference Internationale sur l'Automatisation Industrielle : June 11-13, 2007, Montreal, Canada 2007 / [6] p. [CD-ROM]

Hierarchical fault simulation in digital systems

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina International Symposium on Signals, Circuits and Systems : SCS 2001 : July 10-11, 2001, Iasi, Romania : proceedings 2001 / p. 181-184 : ill

Hierarchical identification of NBTI-critical gates in nanoscale logic

Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes; Jenihhin, Maksim LATW2014 : 15th IEEE Latin-American Test Workshop : Fortaleza, Brazil, March 12th-15th, 2014 2014 / [6] p. : ill

Hierarchical identification of untestable faults in sequential circuits

Raik, Jaan; Ubar, Raimund-Johannes; Krivenko, Anna; Kruus, Margus 10th Euromicro Conference on Digital System Design Architectures, Methods and Tools, DSD 2007 : 29-31 August 2007, Lübeck, Germany : proceedings 2007 / p. 668-671 : ill <http://dx.doi.org/10.1109/DSD.2007.4341539>

High level fault modeling in digital systems

Ubar, Raimund-Johannes; Aarna, Margit; Brik, Marina; Raik, Jaan Synergies between Information and Automation : 49. Internationales Wissenschaftliches Kolloquium, 27.-30.9.2004, Technische Universität Ilmenau, Germany. Volume 2 2004 / p. 486-491

High-frequency current sensor for power network on-line mea[s]urements

Kütt, Lauri; Järvi, Jaan; Vaimann, Toomas; Shafiq, Muhammad; Lehtonen, Matti; Kilter, Jako Proceedings of the 13th International Scientific Conference Electric Power Engineering 2012 : EPE 2012 : Brno. Vol. 1 2012 / p. 367-371 : ill https://www.researchgate.net/publication/262674502_High-Frequency_Current_Sensor_for_Power_Network_On-line_Measurements

High-level decision diagram based fault models for targeting FSMs

Raik, Jaan; Ubar, Raimund-Johannes; Viilukas, Taavi 9th EUROMICRO Conference on Digital Systems Design : Architectures, Methods and Tools (DSD 2006) : 30 August 2006-1 September 2006, Cavtat near Dubrovnik, Croatia : proceedings 2006 / p. 353-358 : ill <http://dx.doi.org/10.1109/DSD.2006.60>

High-level design error diagnosis using backtrace on decision diagrams

Raik, Jaan; Repinski, Urmas; Ubar, Raimund-Johannes; Jenihhin, Maksim; Tšepurov, Anton 28th Norchip Conference : Tampere, Finland, 15-16 November 2010 : conference program and papers 2010 / [4] p. : ill

<http://dx.doi.org/10.1109/NORCHIP.2010.5669486>

High-level fault diagnosis in RISC processors with Implementation-Independent Functional Test

Oyeniran, Adeboye Stephen; Jenihhin, Maksim; Raik, Jaan; Ubar, Raimund-Johannes 2022 IEEE Computer Society Annual Symposium on VLSI (ISVLSI) : Nicosia, Cyprus : 04-06 July 2022 / p. 32-37 <https://doi.org/10.1109/ISVLSI54635.2022.00019>

High-level functional test generation for microprocessor modules

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes Proceedings of 26th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2019 : Rzeszów, Poland, June 27 - 29, 2019 / p. 356-361 : ill <https://doi.org/10.23919/MIXDES.2019.8787131>

High-level modeling and testing of multiple control faults in digital systems

Jasnetski, Artjom; Oyeniran, Adeboye Stephen; Tšertov, Anton; Schölzel, Mario; Ubar, Raimund-Johannes Formal proceedings of the 2016 IEEE 19th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 20-22, 2016, Košice, Slovakia 2016 / [6] p. : ill <http://dx.doi.org/10.1109/DDECS.2016.7482445>

High-level path activation technique to speed up sequential circuit test generation

Raik, Jaan; Ubar, Raimund-Johannes European Test Workshop 1999 : proceedings, May 25-28, 1999, Constance, Germany 1999 / p. 84-89 : ill <https://ieeexplore.ieee.org/document/804289>

High-level test generation for processing elements in many-core systems

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Azad, Siavoosh Payandeh; Raik, Jaan 12th International Symposium on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC2017), July 12-14, 2017, Madrid, Spain : proceedings 2017 / 8 p. : ill <http://dx.doi.org/10.1109/ReCoSoC.2017.8016156>

High-speed logic level fault simulation

Ubar, Raimund-Johannes; Devadze, Sergei Design and test technology for dependable systems-on-chip 2011 / p. 310-335 : ill <https://www.igi-global.com/chapter/high-speed-logic-level-fault/51407>

Hilbert transform, an effective replacement of Park's vector modulus for the detection of rotor faults

Asad, Bilal; Vaimann, Toomas; Kallaste, Ants; Rassõlkin, Anton; Belahcen, Anouar 2019 Electric Power Quality and Supply Reliability Conference (PQ) & 2019 Symposium on Electrical Engineering and Mechatronics (SEEM), Kärdla, Estonia, June 12-15, 2019 : proceedings 2019 / 4 p. : ill <https://doi.org/10.1109/PQ.2019.8818227>

Hispaania stsenaarium: miks elektrisüsteemid ootamatult kustuvad

Landsberg, Mart postimees.ee 2025 <https://tehnika.postimees.ee/8239729/eksperdi-ulevaade-hispaania-stsenaarium-miks-elektrisusteemid-ootamatult-kustuvad>

Holistic approach for Fault-Tolerant Network-on-Chip based many-core systems [Online resource]

Azad, Siavoosh Payandeh; Niazmand, Behrad; Raik, Jaan; Jervan, Gert; Hollstein, Thomas arXiv.org 2016 / [8] p. : ill

Hybrid built-in self-test : methods and tools for analysis and optimization of BIST = Sisseehitatud hübriidne isetestimine : meetodid ja vahendid analüüsiks ning optimeerimiseks

Orasson, Elmet 2007 https://www.ester.ee/record=b2305436*est

Hybrid FEA-Simulink modelling of permanent magnet assisted synchronous reluctance motor with unbalanced magnet flux

Pando-Acedo, Jaime; Rassõlkin, Anton; Lehtikoinen, Antti; Vaimann, Toomas; Kallaste, Ants; Romero-Cadaval, Enrique; Belahcen, Anouar 2019 IEEE 12th International Symposium on Diagnostics for Electrical Machines, Power Electronics and Drives (SDEMPED), 27-30 Aug. 2019, Toulouse, France : proceedings 2019 / p. : 174-180 : ill <https://doi.org/10.1109/DEMPED.2019.8864925>

Identification and location of PD defects in medium voltage underground power cables using high frequency current transformer

Shafiq, Muhammad; Kiitam, Ivar; Taklaja, Paul; Kütt, Lauri; Kauhaniemi, Kimmo; Palu, Ivo IEEE Access 2019 / art. 8771171, p. 103608 - 103618 : ill <https://doi.org/10.1109/ACCESS.2019.2930704> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Impact of faults and different operating conditions on current parameters in case of broken rotor bars

Kudelina, Karolina 21st International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of energy and geotechnology. III" : Pärnu, Estonia, June 15-18, 2022 / p. 41-42 : ill https://www.ester.ee/record=b5504019*est

Implementation of protection features for a modular bidirectional solid-state battery disconnecter

Dsa, Daniel; Chinnusamy, Abhinav; Banavath, Satish Naik; Carvalho da Silva, Edivan Laercio IEEE journal of emerging and selected topics in power electronics 2024 <https://doi.org/10.1109/JESTPE.2024.3502157>

Implementation-independent functional test generation for RISC microprocessors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 82-87 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920323>

Implementation-independent test generation for a large class of faults in RISC processor modules

Jenihhin, Maksim; Oyeniran, Adeboye Stephen; Raik, Jaan; Ubar, Raimund-Johannes 24th Euromicro Conference on Digital System Design (DSD) 2021 <https://doi.org/10.1109/DSD53832.2021.00090>

An improved estimation methodology for hybrid BIST cost calculation

Jervan, Gert; Peng, Zebo; Ubar, Raimund-Johannes; Korelina, Olga Proceedings [of] 22nd NORCHIP Conference : Oslo, Norway, 8-9 November 2004 2004 / p. 297-300 : ill <https://ieeexplore.ieee.org/document/1423882>

Improved fault classification and localization in power transmission networks using vae-generated synthetic data and machine learning algorithms

Khan, Muhammad Amir; Asad, Bilal; Vaimann, Toomas; Kallaste, Ants; Pomarnacki, Raimondas; Hyunh, Van Khang Machines 2023 / art. 963 <https://doi.org/10.3390/machines11100963> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Improved fault emulation for synchronous sequential circuits

Raik, Jaan; Ellervee, Peeter; Tihhomirov, Valentin; Ubar, Raimund-Johannes Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 72-78 : ill

Improving the confidence level in functional safety simulation tools for ISO 26262

Bagbaba, Ahmet Cagri; Augusto da Silva, Felipe; Sauer, Christian 2018 Design and Verification Conference (DVCON) Europe : [proceedings] 2018 / 6 p. : ill <https://dvcon-proceedings.org/document/improving-the-confidence-level-in-functional-safety-simulation-tools-for-iso-26262/> <https://zenodo.org/record/3361607#.Y0PHFnZByHs>

Insulation durability and measurement of partial discharge = Isolatsiooni vastupidavus ja osalahenduste mõõtmise

Kiitam, Ivar 2021 https://www.ester.ee/record=b5473274*est <https://digikogu.taltech.ee/et/Item/401e6d0b-f51d-488f-b0d6-2e2bdb8f9496> <https://doi.org/10.23658/taltech.62/2021>

Integrated modelling, fault management, verification and reliable design environment for cyber-physical systems

Raik, Jaan; Rauwerda, Gerard; Zhao, Yong; Shibin, Konstantin MEDIAN Finale : Workshop on Manufacturable and Dependable Multicore Architectures at Nanoscale : November 10-11, 2015, Tallinn, Estonia 2015 / p. 74

Intelligent diagnostic centers: a new way to distributed fault-tolerance

Varkonyi-Koczy, Annamaria R.; Tilly, K.; Dobrowiecki, Tadeusz; Vadasz, B.; Kiss, I. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 365-368: ill

Internet based test generation and fault simulation

Ivask, Eero; Ubar, Raimund-Johannes; Raik, Jaan; Schneider, Andre IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Győr, Hungary, April 18-20, 2001 2001 / p. 57-60 : ill

Internet-based collaborative test generation with MOSCITO [Electronic resource]

Schneider, Andre; Ivask, Eero; Miklos, P.; Raik, Jaan; Diener, Karl-Heinz; Ubar, Raimund-Johannes; Cibakova, Tatiana; Gramatova, Elena SIGDA publications on CD-ROM : DATE'02 : Design, Automation and Test in Europe, Paris, France, March 4-8, 2002 2002 / [6] p. [CD-ROM] https://www.cecs.uci.edu/~papers/date07/PAPERS/2002/DATE02/PDFFILES/02E_2.PDF

Investigating the progression of insulation degradation in power cable based on partial discharge measurements

Hassan, Waqar; Shafiq, Muhammad; Hussain, Ghulam Amjad; Choudhary, Maninder; Palu, Ivo Electric power systems research 2023 / art. 109452 <https://doi.org/10.1016/j.epsr.2023.109452> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Invited paper: System-Wide Fault Management based on IEEE P1687 IJTAG

Jutman, Artur; Devadze, Sergei; Alekseyev, Jevgeni 6th International Workshop on Reconfigurable Communication-centric Systems-on-Chip (ReCoSoC) : 20-22 June 2011, Montpeillier, France 2011 / [4] p.: ill <https://ieeexplore.ieee.org/document/5981520>

IoT based tools and methods for electrical machine diagnostics = Asjade interneti põhised tööriistad ja meetodid elektrimasinate diagnostikaks

Raja, Hadi Ashraf 2023 <https://doi.org/10.23658/taltech.20/2023> <https://digikogu.taltech.ee/et/Item/3015334f-c32b-43ae-ba2d-bfcd536aba5> https://www.ester.ee/record=b5558656*est

Kordsete rikete diagnostika järjestikülülitustes

Puulinn, S.; Ubar, Raimund-Johannes XXIX vabariiklik üliõpilaste teaduslik- tehniline konverents 30. märtsist - 1. aprillini 1977 : ettekannete teesid 1977 / lk. 43 https://www.ester.ee/record=b2449987*est

Kui pikk peab olema elektrikatkestus

Valdna, Vello Tallinna Tehnikaülikooli aastaraamat 2003 2004 / lk. 169-170

Kui pikk peab olema elektrikatkestus : [poliitikut peavad väärtustama reaalaridust, insenerikoolitust ja tehnikateadusi]

Valdna, Vello Postimees 2003 / 23. sept., lk. 13 <https://arvamus.postimees.ee/2049577/kui-pikk-peab-olema-elektrikatkestus>

Kuidas teha peedist pesumasinale trumlit? Auvere elektriiaam neelab veel miljoneid ega hakka niipea normaalselt tööle!

Niitra, Nils ohtuleht.ee 2023 / lk. 4-5 [Kuidas teha peedist pesumasinale trumlit? Auvere elektriiaam neelab veel miljoneid ega hakka niipea normaalselt tööle!](https://ohtuleht.ee/2023/04/05/kuidas-teha-peedist-pesumasinale-trumlit-auvere-elektriiaam-neelab-veel-miljoneid-e-ga-hakka-niipea-normaalselt-tooe/)

Kuumvahetusmoodulid

Toomsalu, Arvo A & A 1999 / 4, lk. 13-15 https://artiklid.elnet.ee/record=b1002041*est

Localization of single-gate design errors in combinational circuits by diagnostic information about stuck-at faults

Ubar, Raimund-Johannes; Borriane, Dominique Proceedings of the 2nd International Workshop on Design and Diagnostics of Electronic Circuits and Systems, Szczyrk, Poland, September 2-4, 1998 1998 / p. 73-79
https://www.researchgate.net/publication/238687832_Localization_of_Single_Gate_Design_Errors_in_Combinational_Circuits_by_Diagnostic_Information_about_Stuck-at_Faults

Logic simulation and fault collapsing with shared structurally synthesized BDDs

Mironov, Dmitri; Ubar, Raimund-Johannes; Raik, Jaan 19th IEEE European Test Symposium (ETS) : May 26th-30th, 2014, Paderborn, Germany : proceedings 2014 / [2] p. : ill

Logic-based implementation of fault-tolerant routing in 3D Network-on-Chips

Niazmand, Behrad; Azad, Siavoosh Payandeh; Flich, Jose; Raik, Jaan; Jervan, Gert; Hollstein, Thomas 2016 Tenth IEEE/ACM International Symposium on Networks-on-Chip (NOCS) : Nara, Japan, 31 August - 2 September 2016 2016 / [8] p. : ill
<https://doi.org/10.1109/NOCS.2016.7579317>

Londoni kiirabi automaatse edastussüsteemi läbikukkumine 1992. aastal

Nestor, Triin A & A 2007 / 5, lk. 18-27 https://artiklid.elnet.ee/record=b1021106*est

Machine learning clustering techniques for selective mitigation of critical design features

Lange, Thomas; Balakrishnan, Aneesh; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 7 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159751>

Machine learning to tackle the challenges of transient and soft errors in complex circuits

Lange, Thomas; Balakrishnan, Aneesh; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 2019 IEEE 25th International Symposium on On-Line Testing and Robust System Design (IOLTS), 1-3 July 2019, Greece 2019 / p. 7-14 : ill
<https://doi.org/10.1109/IOLTS.2019.8854423>

Machinery risk assessment integration with design and development methods for risk and potential failure reduction considering safety and efficiency

Sivitski, Alina; Põdra, Priit Modern materials and manufacturing 2023 : Tallinn, Estonia, 2-4 May 2023 2024 / art. 030013
<https://doi.org/10.1063/5.0189257> [Journal metrics at Scopus](#) [Article at Scopus](#)

Macro level defect-oriented diagnosability of digital circuits

Kostin, Sergei; Ubar, Raimund-Johannes; Raik, Jaan BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 149-152 : ill

Magnetic equivalent circuit and Lagrange interpolation function modeling of induction machines under broken bar faults

Hemeida, Ahmed; Billah, Md Masum; Kudelina, Karolina; Asad, Bilal; Naseer, Muhammad Usman; Guo, Baocheng; Martin, Florian; Rasilo, Paavo; Belahcen, Anouar IEEE transactions on magnetics 2024 / art. 8200704, 4 p
<https://doi.org/10.1109/TMAG.2023.3306207> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Main bird excrement contamination type causing insulator flashovers in 110 kV overhead power lines in Estonia

Taklaja, Paul; Oidram, Rein; Niitsoo, Jaan; Palu, Ivo Oil shale 2013 / p. 211-224 : ill https://artiklid.elnet.ee/record=b2631738*est
<https://doi.org/10.3176/oil.2013.2S.03> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Main gear-faults in industrial hitara

Autsoo, Siarhei 20th International Symposium "Topical problems in the field of electrical and power engineering. Doctoral school of energy and geotechnology. III" : Tallinn, Estonia, September 8-10, 2021 2022 / p. 17-18 : ill https://www.ester.ee/record=b5457278*est

Mapping faults in hierarchical testing of digital systems

Ubar, Raimund-Johannes International Conference on Computer, Communication and Control Technologies CCCT'03 and the 9th International Conference on Information Systems, Analysis and Synthesis ISAS'03 : July 31 - August 1-2, Orlando, Florida, USA : proceedings. Volume I, Computing/Information Systems and Technologies 2003 / p. 14-19 : ill

Marginal PCB assembly defect detection on DDR3/4 memory bus

Odintsov, Sergei; Jutman, Artur; Devadze, Sergei 2017 IEEE International Test Conference (ITC 2017) : Forth Worth, Texas, USA, 31 October - 2 November 2017 / p. 238-247 : ill <https://doi.org/10.1109/TEST.2017.8242070> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

A mathematical model for the determination of leakage in mains and water distribution networks

Koppel, Tiit; Ainola, Leo; Puust, Raido Proceedings of the Estonian Academy of Sciences. Engineering 2007 / 1, p. 3-16 : ill

Mathematical modelling of three phase squirrel cage induction motor and related signal processing for fault diagnostics = Kolmefaasilise lühisrootoriga asünkroonmootori matemaatiline modelleerimine ning lähtuv rikkediagnostiline signaalitöötlus

Asad, Bilal 2021 <https://digikogu.taltech.ee/et/Item/8b5869c8-de30-4380-a0c6-8a6a2d6b6ff3> https://www.ester.ee/record=b5452432*est <https://doi.org/10.23658/taltech.40/2021>

Me peame rääkima Facebookist

Kivi, Krister Postimees 2021 / Lk. 17 https://www.ester.ee/record=b1072778*est

Metallitööstus pani tehisintellekti seadmetest rikkeid otsima [Võrguväljaanne]

toostusuudised.ee 2022 / Lk. 14 [Metallitööstus pani tehisintellekti seadmetest rikkeid otsima](#)

Methods for improving the accuracy and efficiency of fault simulation in digital systems = Meetodid digitaalsüsteemide rikete simuleerimise täpsuse ja efektiivsuse tõstmiseks

Kõusaar, Jaak 2019 <https://digi.lib.ttu.ee/i/?11667>

Methods of condition monitoring and fault detection for electrical machines

Kudelina, Karolina; Asad, Bilal; Vaimann, Toomas; Rassõlkin, Anton; Kallaste, Ants; Khang, Huynh Van Energies 2021 / art. 7459, 20 p. : ill <https://doi.org/10.3390/en14227459> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Middle-frequency isolation transformer design issues for the high-voltage DC/DC converter

Vinnikov, Dmitri; Laugis, Juhan; Galkin, Ilja PESC 08 : 39th IEEE Annual Power Electronics Specialists Conference : Rhodes, Greece, 15-19 June 2008 : book of one page paper summaries 2008 / p. 304 : ill <https://ieeexplore.ieee.org/document/4592226>

Middle-frequency isolation transformer design issues for the high-voltage DC/DC converter

Vinnikov, Dmitri; Laugis, Juhan; Galkin, Ilja Proceedings of 2008 IEEE 39th Annual Power Electronics Specialists Conference : PESC 2008 : Rhodes, Greece, 15-19 June 2008 / p. 1930-1936 <https://ieeexplore.ieee.org/document/4592226>

Miks Facebook ei tööta? Põhjuseks võib olla ebaõnnestunud tarkvarauuendus [Võrguväljaanne]

Veedla, Alice delfi.ee 2021 ["Miks Facebook ei tööta? Põhjuseks võib olla ebaõnnestunud tarkvarauuendus"](#)

Minimisation of higher harmonics in high power saturable reactors for AC power transmission lines

Tellinen, Juhan; Järvik, Jaan Power Quality '98 : [International Conference, June 18-20, 1998] : Hyderabad, India / The Institute of Electrical and Electronics Engineers, Inc 1998 / p. 133-138: ill <https://ieeexplore.ieee.org/document/710367>

Minimization of the high-level fault model for microprocessor control parts [Online resource]

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Medaiyese, Olusiji BEC 2018 : 2018 16th Biennial Baltic Electronics Conference (BEC) : proceedings of the 16th Biennial Baltic Electronics Conference, October 8-10, 2018 / 4 p.: ill <https://doi.org/10.1109/BEC.2018.8600980>

Missugused varutoiteallikad valida, et elada üle elektrikatkestused

Thalfeldt, Martin; Rosin, Argo maakodu.delfi.ee 2023 [Missugused varutoiteallikad valida, et elada üle elektrikatkestused](#)

Mixed hierarchical-functional fault models for targeting sequential cores

Raik, Jaan; Ubar, Raimund-Johannes; Viilukas, Taavi; Jenihhin, Maksim Journal of systems architecture 2008 / 3/4, p. 465-477 : ill <https://www.sciencedirect.com/science/article/abs/pii/S1383762107001166>

Mixed-level defect simulation in data-paths of digital systems

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina 23rd International Conference on Microelectronics : MIEL 2002, Niš, Yugoslavia, 12-15 May 2002 : proceedings. Volume 2 2002 / p. 617-620 : ill <https://ieeexplore.ieee.org/document/1003333>

Model verification for analysis of wind power impact to transient stability in isolated power system using combined relay protection and dynamics modelling approach

Maripuu, Rain; Tsernobrovkin, Oleg; Palu, Ivo; Kilter, Jako PQ2012 : 8th International Conference : 2012 Electric Power Quality

and Supply Reliability : June 11-13, 2012, Tartu, Estonia : conference proceedings 2012 / p. 169-174 : ill
<https://ieeexplore.ieee.org/stamp/stamp.jsp?arnumber=6256222>

Modeling microprocessor faults on high-level decision diagrams [Electronic resource]

Ubar, Raimund-Johannes; Raik, Jaan; Jutman, Artur; Jenihhin, Maksim; Istenberg, Martin; Wuttke, Heinz-Dietrich DSN 2008 : supplemental : 2008 IEEE International Conference on Dependable Systems & Networks With FTCS & DCC (DSN) : June 24-27, 2008, Anchorage, Alaska 2008 / p. C17-C22 : ill. [CD-ROM]
[https://webhost.laas.fr/TSF/WDSN08/2ndWDSN08\(LAAS\)_files/Slides/WDSN08S-04-Ubar.pdf](https://webhost.laas.fr/TSF/WDSN08/2ndWDSN08(LAAS)_files/Slides/WDSN08S-04-Ubar.pdf)

Modeling sequential circuits with shared structurally synthesized BDDs

Ubar, Raimund-Johannes; Marenkov, Mihail; Mironov, Dmitri; Viies, Vladimir Proceedings of 2014 9th International Design & Test Symposium (IDT) : Sheraton Club des Pins Hotel, Algiers, Algeria, December 16-18, 2014 / p. 130-135 : ill

Modified winding function-based model of squirrel cage induction motor for fault diagnostics

Asad, Bilal; Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants; Rassõlkin, Anton; Iqbal, Muhammad Naveed IET electric power applications 2020 / p. 1722-1734 <https://doi.org/10.1049/iet-epa.2019.1002> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Mootoririkkega uurimislav Salme ootab tormivarjuse ilma paranemist [Võrguväljaanne]

postimees.ee 2021 ["Mootoririkkega uurimislav Salme ootab tormivarjuse ilma paranemist"](#)

Multi-level fault simulation of digital systems on decision diagrams

Ubar, Raimund-Johannes; Raik, Jaan; Ivask, Eero; Brik, Marina The First IEEE International Workshop on Electronic Design, Test and Applications : DELTA 2002, 29-31 January 2002, Christchurch, New Zealand : proceedings 2002 / p. 86-91 : ill

Multi-level test generation and fault diagnosis in digital systems

Ubar, Raimund-Johannes 1992

Multi-level test generation for digital systems at system, circuit and defect levels

Ubar, Raimund-Johannes Proceedings of the 7th International Scientific Conference "Theory and Technique of Information Transmission, Reception and Processing" : Tuapse, October 1-4, 2001 / p. 286-288

Multi-loop model reference adaptive control of fractional-order PID control systems

Alagoz, Baris Baykant; Tepljakov, Aleksei; Petlenkov, Eduard; Yeroglu, Celaledin 2017 40th International Conference on Telecommunications and Signal Processing TSP : July 5-7, 2017, Barcelona, Spain 2017 / p. 702-705 : ill
<https://doi.org/10.1109/TSP.2017.8076078>

Multiple control fault testing in digital systems with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen 2016 IEEE International Conference on Automation, Quality and Testing, Robotics (AQTR) : THETA 20th edition : 19th-21st May, Cluj-Napoca, Romania : proceedings 2016 / [6] p. : ill
<http://dx.doi.org/10.1109/AQTR.2016.7501287>

Multiple fault testing in systems-on-chip with high-level decision diagrams

Ubar, Raimund-Johannes; Oyeniran, Adeboye Stephen; Schölzel, Mario; Vierhaus, Heinrich Theodor Proceedings of 2015 10th International Design & Test Symposium (IDT) : Dead Sea, Jordan, 14-16 December 2015 / p. 66-71 : ill
<http://dx.doi.org/10.1109/IDT.2015.7396738>

Multiple stuck-at-fault detection theorem

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan Proceedings of the 2012 IEEE 15th International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS) : April 18-20, 2012 Tallinn, Estonia 2012 / p. 236-241 : ill

Multiple-objective backtrace for solving test generation constraints

Mekler, A.; Raik, Jaan International Symposium on System-on-Chip : November 19-21, 2003, Tampere, Finland : proceedings 2003 / p. 123-126 : ill <https://ieeexplore.ieee.org/document/1267732>

Naine, kes muudab maailma: noor teadlane loob süsteemi, mis ennetab elektrimasinate rikkeid [Võrguväljaanne]

Keba, Triinu delfi.ee 2022 [Naine, kes muudab maailma: noor teadlane loob süsteemi, mis ennetab elektrimasinate rikkeid](#)

Necessity for implementation of inverse problem theory in electric machine fault diagnosis

Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants SDEMPED 2015 : 10th IEEE International Symposium on Diagnostics for Electric Machines, Power Electronics and Drives : Guarda, Portugal, September 1-4, 2015 : proceedings 2015 / p. 380-385 : ill
<http://dx.doi.org/10.1109/DEMPED.2015.7303718>

New built-in self-test scheme for SoC interconnect

Jutman, Artur; Ubar, Raimund-Johannes; Raik, Jaan The 9th World Multi-Conference on Systemics, Cybernetics and Informatics : WMSCI 2005 : July 10-13, 2005, Orlando, Florida, USA. Vol. IV 2005 / p. 19-24 : ill
https://www.researchgate.net/publication/237375234_New_Built-In_Self-Test_Scheme_for_SoC_Interconnect

New categories of Safe Faults in a processor-based Embedded System

Gürsoy, Cemil Cem; Jenihhin, Maksim; Oyeniran, Adeboye Stephen; Piumatti, Davide; Raik, Jaan; Sonza Reorda, Matteo; Ubar, Raimund-Johannes 2019 22nd International Symposium on Design and Diagnostics of Electronic Circuits & Systems (DDECS), Cluj-Napoca, Romania : proceedings 2019 / 4 p. : ill <https://doi.org/10.1109/DDECS.2019.8724642>

A new measure for calculating multiple fault coverage of microprocessor self-test

Oyeniran, Adeboye Stephen; Odozi, Uzochukwu Eddie; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 75-78 : ill http://www.eester.ee/record=b2150914*est

A new modified berger code for concurrent error detection

Maamar, Ali H.; Russel, Gordon BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 187-190: ill

A new resonant fault current limiter for improved wind turbine transient stability

Demin, Slava; Sitbon, Moshe; Aharon, Ilan; Barbi, Eli; Machlev, Ram; **Belikov, Juri**; Levron, Yoash; Baimel, Dmitry Electric Power Systems Research 2023 / art. 109600, 8 p <https://doi.org/10.1016/j.eprsr.2023.109600> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

New technique for hierarchical identification of untestable faults in sequential circuits

Krivenko, Anna; Ubar, Raimund-Johannes; Raik, Jaan; Kruus, Margus Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK kolmanda aastakonverentsi artiklite kogumik : 25.-26. aprill 2008, Voore külalistemaja 2008 / lk. 155-158 : ill

NoCDepend : a flexible and scalable dependability technique for 3D networks-on-chip

Hollstein, Thomas; Azad, Siavoosh Payandeh; Kogge, Thilo; Ying, Haoyuan; Hofmann, Klaus 2015 IEEE 18th International Symposium on Design and Diagnostics of Electronic Circuits & Systems DDECS 2015 : 22-24 April 2015, Belgrade, Serbia : proceedings 2015 / p. 75-78 : ill <http://dx.doi.org/10.1109/DDECS.2015.30>

Non-intrusive defects identification for the high voltage instrument transformers

Asefi, Sajjad; Kilter, Jako; Landsberg, Mart 2023 IEEE 17th International Conference on Compatibility, Power Electronics and Power Engineering (CPE-POWERENG) 2023 / 5 p <https://doi.org/10.1109/CPE-POWERENG58103.2023.10227493>

Novel approaches to electrical machine fault diagnosis

Vaimann, Toomas; Antonino-Daviu, Jose Alfonso; **Rassõlkin, Anton** Energies 2023 / art. 5641 <https://doi.org/10.3390/en16155641> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

A novel artificial neural networks based automatic adaptive fault detection technique for analog circuits

Petlenkov, Eduard; Jutman, Artur; Nõmm, Sven; Ubar, Raimund-Johannes BEC 2008 : 2008 International Biennial Baltic Electronics Conference : proceedings of the 11th Biennial Baltic Electronics Conference : Tallinn University of Technology : October 6-8, 2008, Tallinn, Estonia 2008 / p. 167-170 : ill

A novel random approach to diagnostic test generation

Osimiry, Emmanuel Ovie; Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 2nd IEEE NORCAS Conference : 1-2 November 2016, Copenhagen, Denmark 2016 / [4] p. : ill <https://doi.org/10.1109/NORCHIP.2016.7792915>

Numerical study on the structural behavior of intact and damaged box beams under four-point bending load

Putranto, Teguh; Kõrgesaar, Mihkel Developments in the Collision and Grounding of Ships and Offshore Structures : Proceedings of the 8th International Conference on Collision and Grounding of Ships and Offshore Structures (ICCGS 2019), 21-23 October, 2019, Lisbon, Portugal 2019 / p. 139-143 <https://www.taylorfrancis.com/books/e/9781003002420/chapters/10.1201/9781003002420-17>

Observer-based residual generation for nonlinear discrete-time systems

Kaldmäe, Arvo; Kotta, Ülle Proceedings of the Estonian Academy of Sciences 2018 / p. 325-336 <https://doi.org/10.3176/proc.2018.4.01> http://www.kirj.ee/public/proceedings_pdf/2018/issue_4/proc-2018-4-325-336.pdf [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Off-line testing of crosstalk induced glitch faults in NoC Interconnects

Bengtsson, Tomas; Kumar, Shashi; **Jutman, Artur; Ubar, Raimund-Johannes** Proceedings [of] 24th IEEE Norchip Conference : Linköping, Sweden, 20-21 November 2006 2006 / p. 221-225 : ill <http://dx.doi.org/10.1109/NORCHIP.2006.329215>

On coverage of timing related faults at board level

Jutman, Artur; Aleksejev, Igor; Devadze, Sergei 2016 21st IEEE European Test Symposium (ETS) : May 23rd-26th 2016, Amsterdam, The Netherlands : proceedings 2016 / [2] p. : ill <https://doi.org/10.1109/ETS.2016.7519295>

On efficient logic-level simulation of digital circuits represented by the SSBDD model

Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes 23rd International Conference on Microelectronics : MIEL 2002, Niš,

Yugoslavia, 12-15 May 2002 : proceedings. Volume 2 2002 / p. 621-624 : ill <https://ieeexplore.ieee.org/document/1003334>

On multiple fault detection in combinational logic circuits

Birger, Alexander BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 225-228

On NBTI-induced aging analysis in IEEE 1687 reconfigurable scan networks

Damljanovic, Aleksa; Squillero, Giovanni; **Gürsoy, Cemil Cem; Jenihhin, Maksim** VLSI-SoC 2019 : 27th IFIP/IEEE International Conference on Very Large Scale Integration : [proceedings] 2019 / p. 335-340 : ill <https://doi.org/10.1109/VLSI-SoC.2019.8920313>

On the estimation of complex circuits functional failure rate by machine learning techniques

Lange, Thomas; **Balakrishnan, Aneesh**; Glorieux, Maximilien; Alexandrescu, Dan; Sterpone, Luca 49th Annual IEEE/IFIP International Conference on Dependable Systems and Networks - DSN 2019 : Supplemental Volume : proceedings 2019 / p. 35-41 : ill <https://doi.org/10.1109/DSN-S.2019.00021>

On-chip sensors data collection and analysis for SoC health management

Shibin, Konstantin; Jenihhin, Maksim; Jutman, Artur; Devadze, Sergei; Tsertov, Anton 2023 IEEE International Symposium on Defect and Fault Tolerance in VLSI and Nanotechnology Systems (DFT) 2023 / 6 p <https://doi.org/10.1109/DFT59622.2023.10313562>

On-line fault classification and handling in IEEE1687 based fault management system for complex SoCs

Shibin, Konstantin; Devadze, Sergei; Jutman, Artur LATS 2016 : 17th IEEE Latin-American Test Symposium, Foz do Iguacu, Brazil, 6th-9th April 2016 2016 / p. 69-74 : ill <https://doi.org/10.1109/LATW.2016.7483342>

Operation of Single-Chip MOSFET and IGBT Devices after failure due to repetitive avalanche [Electronic resource]

Blinov, Andrei; Norrga, Staffan; Tibola, Gabriel EPE'15 ECCE Europe : 8-10 September 2015, Geneva, Switzerland : 17th European Conference on Power Electronics and Applications 2015 / p. 1-9 : ill. [USB] <http://dx.doi.org/10.1109/EPE.2015.7309190>

Optimization of memory-constrained hybrid BIST for testing core-based systems

Jervan, Gert; Kruus, Helena; Orasson, Elmet; Ubar, Raimund-Johannes Proceedings of the IEEE 2nd International Symposium on Industrial Embedded Systems : SIES'2007 : Lisbon, Portugal, 4-6 July 2007 2007 / p. 71-77
<https://ieeexplore.ieee.org/document/4297319>

Overview of e-learning environment for web-based study of testing and diagnostics of digital systems

Jutman, Artur; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Microelectronics education : proceedings of the 5th European Workshop on Microelectronics Education, held in Lausanne, Switzerland, April 15-16, 2004 2004 / p. 253-258 : ill
https://link.springer.com/chapter/10.1007/978-1-4020-2651-5_41

Overview of e-learning environment for web-based study of testing and diagnostics of digital systems

Jutman, Artur; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich 5th European Workshop on Microelectronics Education - EWME 2004, Lausanne, 2004 2004 / p. 173-176 https://link.springer.com/chapter/10.1007/978-1-4020-2651-5_41

Parallel critical path tracing fault simulation

Ubar, Raimund-Johannes 39. Internationales Wissenschaftliches Kolloquium : 27.-30.09.1994. Bd. 1, Vortragsreihen 1994 / S. 399-404

Parallel critical path tracing fault simulation in sequential circuits

Kõusaar, Jaak; Ubar, Raimund-Johannes; Kostin, Sergei; Devadze, Sergei; Raik, Jaan Proceedings of 25th International Conference MIXED DESIGN OF INTEGRATED CIRCUITS AND SYSTEMS : MIXDES 2018 : Gdynia, Poland, June 21-23, 2018 2018 / p. 305-310 : ill <https://doi.org/10.23919/MIXDES.2018.8436880>

Parallel exact critical path tracing fault simulation with reduced memory requirements

Devadze, Sergei; Ubar, Raimund-Johannes; Raik, Jaan; Jutman, Artur 4th International Conference on Design and Technology of Integrated Systems in Nanoscale Era : DTIS'09 : Cairo, Egypt, April 6-9, 2009 2009 / p. 155-160 : ill
<https://ieeexplore.ieee.org/document/4938046>

Parallel fault analysis on structurally synthesized BDDs

Devadze, Sergei; Ubar, Raimund-Johannes Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuseum 2007 / lk. 47-50 : ill

Parallel fault backtracing for calculation of fault coverage

Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan; Jutman, Artur Proceedings of the ASP-DAC 2008 : [13th] Asia and South Pacific Design Automation Conference 2008 : January 21-24, 2008, COEX, Seoul, Korea 2008 / p. 667-672 : ill
https://www.researchgate.net/publication/221153650_Parallel_fault_backtracing_for_calculation_of_fault_coverage

Parallel fault backtracing for calculation of fault coverage

Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan; Jutman, Artur 43rd International Conference on Microelectronics, Devices and Materials and the Workshop on Electronic Testing : September 12. - September 14.2007, Bled, Slovenia : MIDEM

conference 2007 proceedings 2007 / p. 165-170 : ill

https://www.researchgate.net/publication/221153650_Parallel_fault_backtracing_for_calculation_of_fault_coverage

Parallel fault simulation in digital circuits

Aarna, Margit; **Raik, Jaan; Ubar, Raimund-Johannes** Proc. of 42nd International Scientific Conference of Riga Technical University 2001 / p. 91-94

Parallel fault simulation in digital circuits

Aarna, Margit; **Raik, Jaan; Ubar, Raimund-Johannes** Scientific proceedings of Riga Technical University. 7. serija, Telecommunications and electronics 2001 / p. 91-94 : ill

Parallel X-fault simulation with critical path tracing technique [Electronic resource]

Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan; Jutman, Artur DATE 10 : Design, Automation & Test in Europe : Dresden, Germany, 8-12 March, 2010 2010 / p. 879-884 [CD-ROM] https://www.researchgate.net/publication/221341788_Parallel_X_fault_simulation_with_critical_path_tracing_technique

Performance evaluation of additive manufacturing based test samples for studies of defects in electrical insulation

Shafiq, Muhammad; Taklaja, Paul; Kiitam, Ivar; Tiismus, Hans; Palu, Ivo; Kütt, Lauri 2021 International Conference on Electrical, Computer and Energy Technologies (ICECET) 2021 / 6 | <https://doi.org/10.1109/ICECET52533.2021.9698476>

Platform independent event correlation tool for network management

Vaarandi, Risto NOMS 2002 : 2002 IEEE/IFIP Network Operations and Management Symposium "Management Solutions for the New Communications World" : proceedings 2002 / p. 907-909 <https://ieeexplore.ieee.org/document/1015640>

PMU placement for fault line location using neural additive models—A global XAI technique

Perl, Michael; Sun, Zhenglong; Machlev, Ram; **Belikov, Juri**; Levy, Kfir Yehuda; Levron, Yoash International journal of electrical power and energy systems 2024 / art. 109573, 10 p. : ill <https://doi.org/10.1016/j.ijepes.2023.109573> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Power quality issues in dispersed generation and smart grids

Vaimann, Toomas; Niitsoo, Jaan; Kivipõld, Tanel; Lehtla, Tõnu Elektronika ir elektrotehnika = Electronics and electrical engineering 2012 / p. 23-26 : ill <https://citeseerx.ist.psu.edu/document?repid=rep1&type=pdf&doi=573c03a0753bcfce3929ba739ff032b16882acf5>

Power-constrained hybrid BIST test scheduling in an abort-on-first-fail test environment

He, Zhiyuan; **Jervan, Gert**; Peng, Zebo; Eles, Petru Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 83-86 : ill <https://ieeexplore.ieee.org/document/1559782>

Preliminary analysis of bearing current faults for predictive maintenance : [conference paper]

Kudelina, Karolina 22nd International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology III : Pärnu, Estonia, August 23-26, 2023 2023 / p. 35-36 : ill https://www.ester.ee/record=b5570906*est

Preliminary analysis of global parameters of induction machine for fault prediction in rotor bars

Kudelina, Karolina; Raja, Hadi Ashraf; Autsou, Siarhei; Asad, Bilal; Vaimann, Toomas; Rassõlkin, Anton; Kallaste, Ants 2022 IEEE 20th International Power Electronics and Motion Control Conference (PEMC) : Brasov, Romania, 25-28 Sept. 2022 : proceedings 2022 / p. 243-248 : ill <https://doi.org/10.1109/PEMC51159.2022.9962922>

Preliminary analysis of mechanical bearing faults for predictive maintenance of electrical machines

Kudelina, Karolina; Raja, Hadi Ashraf; Autsou, Siarhei; Naseer, Muhammad Usman; Vaimann, Toomas; Kallaste, Ants; Pomamacki, Raimondas; Hyunh, Van Khang 2023 IEEE 14th International Symposium on Diagnostics for Electrical Machines, Power Electronics and Drives (SDEMPED) 2023 / p. 430-435 : ill <https://doi.org/10.1109/SDEMPED54949.2023.10271451>

ProAct: Progressive Training for Hybrid Clipped Activation Function to Enhance Resilience of DNNs

Mousavi, Seyedhamidreza; **Ahmadilivani, Mohammad Hasan; Raik, Jaan; Jenihhin, Maksim; Daneshtalab, Masoud** arXiv.org 2024 / 12 p. : ill <https://doi.org/10.48550/arXiv.2406.06313>

Protection and common mode voltage of The Push-Pull Partial Power Converter

Abdelrahim Abdelghafour, Omar Mohamed; Vinnikov, Dmitri; Chub, Andrii; Blinov, Andrei IEEE Conference on Power Electronics and Renewable Energy : Luxor, Egypt, February, 19-21, 2023 2023 <https://doi.org/10.1109/CPERE56564.2023.10119636>

Protection of bidirectional Step-Up/Down partial power converter against short circuit and open circuit faults and mode transition issues

Hassanpour, Naser; Chub, Andrii; Blinov, Andrei; Yadav, Neelesh; Hasan, Sayeed; Vinnikov, Dmitri 2024 IEEE 18th International Conference on Compatibility, Power Electronics and Power Engineering (CPE-POWERENG) 2024 / 6 p <https://doi.org/10.1109/CPE-POWERENG60842.2024.10604315>

A public dataset for synchronous motor electrical faults diagnosis with CNN and LSTM reference classifiers

Sun, Zhenglong; Machlev, Ram; Wang, Qianchao; **Belikov, Juri**; Levron, Yoash; Baimel, Dmitry Energy and AI 2023 / art. 100274, 17 p <https://doi.org/10.1016/j.egyai.2023.100274> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Register-transfer level deductive fault simulation using decision diagrams

Reinsalu, Uljana; Raik, Jaan; Ubar, Raimund-Johannes BEC 2010 : 2010 12th Biennial Baltic Electronics Conference : proceedings of the 12th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 4-6, 2010, Tallinn, Estonia 2010 / p. 193-196 : ill

Rejuvenation of nanoscale logic at NBTI-critical paths using evolutionary TPG

Palermo, N.; **Tihomirov, Valentin**; Copetti, Thiago; **Jenihhin, Maksim; Raik, Jaan; Kostin, Sergei** 2015 16th Latin American Test Symposium (LATS 2015) : Puerto Vallarta, Mexico, 25-27 March 2015 2015 / [6] p. : ill <http://dx.doi.org/10.1109/LATW.2015.7102405>

Reliable health monitoring and fault management infrastructure based on embedded instrumentation and IEEE 1687

Jutman, Artur; Shibin, Konstantin; Devadze, Sergei IEEE AUTOTESTCON 2016 : Anaheim, California, USA, September 12-15, 2016 : proceedings 2016 / p. 240-249 : ill <https://doi.org/10.1109/AUTEST.2016.7589605>

Research and training environment for digital design and test

Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Proceedings of the Eighth IASTED International Conference on Computers and Advanced Technology in Education : August 29-31, 2005, Oranjestad, Aruba 2005 / p. 232-237 : ill <https://ieeexplore.ieee.org/document/1408779>

Research environment for teaching digital test

Ivask, Eero; Jutman, Artur; Orasson, Elmet; Raik, Jaan; Ubar, Raimund-Johannes; Wuttke, Heinz-Dietrich Synergies between Information and Automation : 49. Internationales Wissenschaftliches Kolloquium, 27.-30.9.2004, Technische Universität Ilmenau, Germany. Volume 2 2004 / p. 468-473 : ill https://pld.ttu.ee/dildis/publications/IWK'2004_res_inv.pdf

Reversible electrowetting on silanized silicon nitride

Cahill, Brian; Giannitsis, Athanasios; **Land, Raul**; Gastrock, Gunter; Pliquett, Uwe; Frense, Dieter; **Min, Mart**; Beckmann, Dieter Sensors and actuators B. Chemical 2010 / p. 380-386 : ill <https://www.sciencedirect.com/science/article/pii/S092540050800885X>

Riigijuhid, kuhu jääb elektritootmise strateegia?

Rajangu, Väino Eesti Päevaleht 2023 / Lk. 3 https://dea.digar.ee/article/eestipaevaleht/2023/01/10/3.5_Riigijuhid_kuhu_jaab_elektritootmise_strateegia?

Rikkevoolukaitse

Teemets, Raivo 2004 https://www.ester.ee/record=b1961658*est

Rikkevoolukaitse

Teemets, Raivo Ehitaja 1996 / 8, lk. 69-70: ill

Rikkevoolukaitse lülitite paigaldamine

Teemets, Raivo Ehitaja 1996 / 9, lk. 73-74: ill

Rotor fault diagnostic of inverter fed induction motor using frequency analysis

Asad, Bilal; Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants; Rassõlkin, Anton 2019 IEEE 12th International Symposium on Diagnostics for Electrical Machines, Power Electronics and Drives (SDEMPED), 27-30 Aug. 2019, Toulouse, France : proceedings 2019 / p. 127-133 : ill <https://doi.org/10.1109/DEMPED.2019.8864903>

RT-level identification of potentially testable initialization faults

Raik, Jaan; Fujiwara, Hideo; **Krivenko, Anna** The Ninth IEEE Workshop on RTL and High Level Testing (WRTL 2008), Sapporo, Japan 2008 / [6] p https://www.researchgate.net/publication/234032548_RT-level_identification_of_potentially_testable_initialization_faults

RT-level test point insertion for sequential circuits

Raik, Jaan; Govind, Vineeth; **Ubar, Raimund-Johannes** IWoTA 2004 : IEEE 1st International Workshop on Testability Assessment : November 2, 2004, Rennes, France : proceedings 2004 / p. 34-40 : ill <https://ieeexplore.ieee.org/document/1428412>

110 kV õhuliinide isolatsiooni töökindluse analüüs ja töökindluse tõstmise meetodid = The study of 110 kV power grid reliability and the measures to decrease insulation failure

Taklaja, Paul 2012 http://www.ester.ee/record=b2857612*est

SALSy : security-aware layout synthesis

Eslami, Mohammad; Perez, Tiago Diadami; Pagliarini, Samuel Nascimento arXiv.org 2024 / 13 p. : ill <https://doi.org/10.48550/arXiv.2308.06201>

Scalable algorithm for structural fault collapsing in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Orasson, Elmet; Raik, Jaan 2015 IFIP/IEEE International Conference on Very Large Scale Integration (VLSI-SoC) : October 5-7, 2015, Daejeon, Korea 2015 / p. 171-176 : ill

A scalable technique to identify true critical paths in sequential circuits

Ubar, Raimund-Johannes; Kostin, Sergei; Jenihhin, Maksim; Raik, Jaan Proceedings 2017 IEEE 20th International Symposium on Design and Diagnostics of Electronic Circuit & Systems (DDECS) : April 19-21, 2017, Dresden, Germany 2017 / p. 152-157 : ill
<https://ieeexplore.ieee.org/stamp/stamp.jsp?tp=&arnumber=7934553>

Self-diagnosis in digital systems = Isediagnoosivad digitaalsüsteemid

Kostin, Sergei 2012 https://www.ester.ee/record=b2757857*est

Sequential test set compaction in LFSR reseeding

Jutman, Artur; Alekseev, Igor; Raik, Jaan Design and test technology for dependable systems-on-chip 2011 / p. 476-493 : ill
<https://ieeexplore.ieee.org/document/4738292>

7-valued algebra for transition delay fault analysis

Kõusaar, Jaak; Ubar, Raimund-Johannes BEC 2014 : 2014 14th Biennial Baltic Electronics Conference : proceedings of the 14th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 6-8, 2014, Tallinn, Estonia 2014 / p. 89-92 : ill

Shared Structurally Synthesized BDDs for speeding-up parallel pattern simulation in digital circuits

Ubar, Raimund-Johannes; Jürimägi, Lembit; Raik, Jaan 2015 Nordic Circuits and Systems Conference (NORCAS) : NORCHIP & International Symposium on System-on-Chip (SoC) : 1st IEEE NORCAS Conference : 26-28 October 2015, Oslo, Norway 2015 / [4] p. : ill <http://dx.doi.org/10.1109/NORCHIP.2015.7364406>

Shift register based TPG for at-speed interconnect BIST

Jutman, Artur MIEL 2004 : 24th International Conference on Microelectronics : Niš, Serbia and Montenegro, 16-19 May 2004 : proceedings. Volume 2 2004 / p. 751-754 : ill <https://ieeexplore.ieee.org/document/1314941?signout=success>

Short-circuit protection circuits for silicon-carbide power transistors

Sadik, Diane-Perle; Colmenares, Juan; Tolstoy, Georg; Rabkowski, Jacek IEEE transactions on industrial electronics 2016 / p. 1995-2004 : ill <https://doi.org/10.1109/TIE.2015.2506628>

Signal processing and machine learning techniques for predictive maintenance of rotor bars in induction machine

Kudelina, Karolina; Raja, Hadi Ashraf; Rjabtšikov, Viktor; Naseer, Muhammad Usman; Vaimann, Toomas; Kallaste, Ants 2023 International Conference on Electrical Drives and Power Electronics (EDPE) 2023 / 7 p. : ill
<https://doi.org/10.1109/EDPE58625.2023.10274030>

Simple relationship between the breakdown voltage, concentration and junction depth pn diffused junctions

Rang, Toomas Physica status solidi. A, Applied research 1982 / p. K117-K119 : tab., joon https://www.ester.ee/record=b1562026*est

Software-level TMR approach for on-board data processing in space applications

Janson, Karl; Treudler, Carl Johann; Hollstein, Thomas; Raik, Jaan; Jenihhin, Maksim; Fey, Goerschwin 21st IEEE International Symposium on Design and Diagnostics of Electronic Circuits and Systems : DDECS 2018 : Budapest, Hungary 25-27 April, 2018 : proceedings 2018 / p. 147-152 : ill <https://doi.org/10.1109/DDECS.2018.00033>

Sonda tektooniline rike Põhja-Kiviõli karjääris

Sõstra, Ülo; Vaher, Rein XV aprillikonverentsi "Geoloogilise kaardistamise poolsajand" teesid : [30. märts 2007, Tallinn] 2007 / lk. 37-39 : ill

Special session : approximation and fault resiliency of DNN accelerators

Ahmadilivani, Mohammad Hasan; Barbareschi, Mario; Barone, Salvatore; Bosio, Alberto; Daneshtalab, Masoud; Torca, Salvatore Della; Gavarini, Gabriele; Jenihhin, Maksim; Raik, Jaan; Taheri, Mahdi 2023 IEEE 41st VLSI Test Symposium (VTS) : proceedings 2023 / 10 p. : ill <https://doi.org/10.1109/VTS56346.2023.10140043> [Conference proceeding at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Special session: reliability assessment recipes for DNN accelerators

Ahmadilivani, Mohammad Hasan; Bosio, Alberto; Deveautour, Bastien; Dos Santos, Fernando Fernandes; Guerrero-Balaguera, Juan-David; Jenihhin, Maksim; Kritikakou, Angeliki; Sierra, Robert Limas; Raik, Jaan; Taheri, Mahdi 42nd IEEE VLSI Test Symposium, VTS 2024 2024 / 11 p. : ill <https://doi.org/10.1109/VTS60656.2024.10538707> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Spectrum analysis additional vibrations of Cartesian robot by different control modes

Autsou, Siarhei; Vaimann, Toomas; Rassõlkin, Anton; Kudelina, Karolina 2022 18th Biennial Baltic Electronics Conference (BEC) 2022 / 5 l. <https://doi.org/10.1109/BEC56180.2022.9935595>

SSBDDs and double topology for multiple fault reasoning

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan Proceedings of IEEE East-West Design & Test Symposium (EWDTS'2012) : Kharkov, Ukraine, September 14–17, 2012 / p. 23-28 <https://www.semanticscholar.org/paper/SSBDDs-and-Double-Topology-for-Multiple-Fault-Ubar-Kostin/8ba04611a41768f0c277a4ba46ca666132fc2f65>

Stator voltage analysis of frequency converter fed induction generator with broken rotor bars

Vaimann, Toomas; Belahcen, Anouar; Martinez, Javier; Kilk, Aleksander 13th International Symposium "Topical Problems in the Field of Electrical and Power Engineering." Doctoral School of Energy and Geotechnology II : Pärnu, Estonia, January 14-19, 2013 / p. 249-251 : ill

Studing the impact of gearbox faults on the operations of the cartesian robot

Autsoo, Siarhei 22nd International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology III : Pärnu, Estonia, August 23-26, 2023 / p. 17-18 : ill https://www.ester.ee/record=b5570906*est

Study of overvoltages upon single-phase ground fault initialisation and arcing processes on MV networks with isolated neutral

Kütt, Lauri; Järvi, Jaan; Sepping, Eino The 4th International Conference Electric Power Quality and Supply Reliability : August 29...31, 2004, Pedase, Estonia : proceedings 2004 / p. 139-143 : ill

Study of the effects of single phase ground faults to the voltage transformers in the 10 kV medium voltage power networks

Janson, Kuno; Järvi, Jaan; Külm, Evald; Kütt, Lauri; Šklovski, Jevgeni 48. Internationales Wissenschaftliches Kolloquium, 22.-25.09.2003, Technische Universität Ilmenau, Germany 2003 / p. 583-584 : ill

Study of the effects of single phase ground faults to the voltage transformers in the 10 kV medium voltage power networks [Electronic resource]

Janson, Kuno; Järvi, Jaan; Külm, Evald; Kütt, Lauri; Šklovski, Jevgeni 48. Internationales Wissenschaftliches Kolloquium, 22.-25.09.2003, Technische Universität Ilmenau, Germany : proceedings and our portrait 2003 / [10] p. : ill. [CD-ROM]

Study of transformer overvoltages under single-phase earth faults in 6...35 kV networks with insulated neutral point [Electronic resource]

Janson, Kuno; Järvi, Jaan; Kalda, Heljut; Külm, Evald; Šklovski, Jevgeni Electric Power Engineering 2003 : 5th International Scientific Conference : January 28-29, 2003, Beskydy Pension, Visalaje, Czech Republic : held by occasion of 25th Anniversary of Department of Electrical 2003 / [17] p. : ill. [CD-ROM]

Suppression of voltage flicker by saturable reactor operating under forced magnetization [Electronic resource]

Bolgov, Viktor; Järvi, Jaan EUROCON 2007 : the International Conference on Computer as a Tool : September 9-12, 2007, Warsaw, Poland : proceedings 2007 / p. 1417-1422 : ill. [CD-ROM] <https://ieeexplore.ieee.org/document/4400513>

A survey of broken rotor bar fault diagnostic methods of induction motor

Asad, Bilal; Vaimann, Toomas; Rassõlkin, Anton; Kallaste, Ants; Belahcen, Anouar Scientific Journal of Riga Technical University. Electrical, control and communication engineering 2018 / p. 117–124 : ill <https://doi.org/10.2478/ecce-2018-0014>

A survey on UAV computing platforms : a hardware reliability perspective

Ahmed, Foisal; Jenihhin, Maksim Sensors 2022 / art. 6286 <https://doi.org/10.3390/s22166286> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Synthesis of multiple fault oriented test groups from single fault test sets [Electronic resource]

Ubar, Raimund-Johannes; Kostin, Sergei; Raik, Jaan 2013 8th International Conference on Design & Technology of Integrated Systems in Nanoscale Era (DTIS) : 26-28 March 2013, Abu Dhabi, UAE 2013 / p. 36-41 : ill [CD-ROM]

A synthesis-agnostic behavioral fault model for high gate-level fault coverage

Karputkin, Anton; Raik, Jaan 2016 Design, Automation & Test in Europe Conference & Exhibition (DATE) : proceedings 2016 / p. 1124-1127 : ill <https://ieeexplore.ieee.org/document/7459477/figures#figures>

A synthetic, hierarchical approach for modelling and managing complex systems' quality and reliability = Sünteetiline, hierarhiline lähenemine keerukate süsteemide kvaliteedi ja töökindluse modelleerimiseks ja haldamiseks

Balakrishnan, Aneesh 2022 <https://doi.org/10.23658/taltech.11/2022> <https://digikogu.taltech.ee/et/item/a594d3ec-0e6b-4a78-819a-fe1f47992612>

System modelling and measurement under the view of design of testability and fault diagnosis of analog circuits

Liu, Ji-Gou; Frühauf, Uwe BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 295-298 : ill

Teaching diagnostic modeling of digital systems with decision diagrams [Electronic resource]

Ubar, Raimund-Johannes; Raik, Jaan; Mironov, Dmitri; Evartson, Teet; Orasson, Elmet; Aarna, Margit; Wuttke, Heinz-Dietrich

Teaching digital system test

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Kruus, Margus The 27th EAAEIE Annual Conference : June 7-9, 2017, Grenoble 2017 / [6] p

Techniques for robust routing, communication and computation in multiprocessor systems = Robustse marsruutimise, side ja arvutuse tehnikad mitneprotsessorilistes süsteemides

Janson, Karl 2021 https://www.ester.ee/record=b5396084*est <https://digikogu.taltech.ee/et/Item/c9091d5c-dcd8-4b21-95a7-84ead85241e6> <https://doi.org/10.23658/taltech.3/2021>

Tehisintellekt pandi metalliette võttes rikkeid otsima, et vähendada tootmiskulusid [Võrguväljaanne]

am.ee 2022 [Tehisintellekt pandi metalliette võttes rikkeid otsima, et vähendada tootmiskulusid](#)

Test configurations for diagnosing faulty links in NoC switches

Raik, Jaan; Ubar, Raimund-Johannes; Govind, Vineeth 12th IEEE European Test Symposium ETS 2007 : 20-24 May 2007, Freiburg, Germany : proceedings 2007 / p. 29-34 : ill <http://dx.doi.org/10.1109/ETS.2007.41>

Test configurations for diagnosing faulty links in NoC switches

Raik, Jaan; Ubar, Raimund-Johannes; Govind, Vineeth Info- ja kommunikatsioonitehnoloogia doktorikooli IKTDK teise aastakonverentsi artiklite kogumik : 11.-12. mai 2007, Viinistu kunstimuuseum 2007 / lk. 33-37 : ill

Test generation for control faults in digital systems

Dušina, Julia; Brik, Marina BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 325-330: ill

Test generation for finite state machines

Ubar, Raimund-Johannes; Brik, Marina BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 233-236: ill

Test methods for crosstalk-induced delay and glitch faults in network-on-chip interconnects implementing asynchronous communication protocols

Bengtsson, Tomas; Kumar, Shashi; **Ubar, Raimund-Johannes; Jutman, Artur**; Peng, Zebo IET computers and digital techniques 2008 / 6, p. 445-460 https://www.diva-portal.org/smash/record.jsf?dswid=5073&aq2=%5B%5B%5D%5D&c=39&af=%5B%5D&searchType=SIMPLE&sortOrder2=title_sort_asc&language=en&pid=diva2%3A290043&aq=%5B%5B%7B%22personId%22%3A%22authority-person%3A23389%22%7D%5D%5D&sf=all&aqe=%5B%5D&sortOrder=author_sort_asc&onlyFullText=false&noOfRows=50

Test pattern generation at the behavioral level from VHDL circuit description containing several processes

Gramatova, Elena; Bezakova, Jana; Cibakova, Tatiana BEC'96 : the 5th Biennial Baltic Electronics Conference, October 7-11, 1996, Tallinn, Estonia : proceedings 1996 / p. 145-148

Testing of systems using software

Ubar, Raimund-Johannes Concise encyclopedia of software engineering 1993 / p. 352-356

The analysis of integrating sigma-delta ADC noise

Gutnikov, V.S.; Krivchenko, T.I. BEC : Baltic Electronics Conference : proceedings of the 4th Biennial Conference, October 9-14, 1994, Tallinn (Estonia). 1 1994 / p. 201-206: ill

The investigation of the Therac-25 accidents

Zdanov, Vassili A & A 2007 / 6, lk. 20-32 : ill https://artiklid.elnet.ee/record=b1021179*est

The study about indefinite fault causes in Estonian 110 kV power grid

Taklaja, Paul; Oidram, Rein PQ2010 : 7th International Conference "2010 Electric Power Quality and Supply Reliability" : June 16-18, 2010, Kuressaare, Estonia 2010 / p. 177-182 : ill

3D parallel fault simulation

Gorev, Maksim; Ubar, Raimund-Johannes Proceedings of the 8th Annual Conference of the Estonian National Doctoral School in Information and Communication Technologies : December 5-6, 2014, Rakvere 2014 / p. 39-42 : ill

3D permeance model of induction machines taking into account saturation effects and its connection with stator current and shaft speed spectra

Martinez, Javier; **Belahcen, Anouar**; Arkkio, Antero IET electric power applications 2015 / p. 20-29 : ill <http://dx.doi.org/10.1049/iet-epa.2014.0013>

A tool for random test generation targeting high diagnostic resolution

Osimiry, Emmanuel Ovie; Kostin, Sergei; Raik, Jaan; Ubar, Raimund-Johannes BEC 2016 : 2016 15th Biennial Baltic Electronics Conference : proceedings of the 15th Biennial Baltic Electronics Conference : Tallinn University of Technology, October 3-5, 2016, Tallinn, Estonia 2016 / p. 79-82 : ill http://www.ester.ee/record=b2150914*est

A tool set for teaching design-for-testability of digital circuits

Kostin, Sergei; Orasson, Elmet; Ubar, Raimund-Johannes EWME 2016 : 11th European Workshop on Microelectronics Education : May 11-13, 2016, Southampton, UK 2016 / [6] p. : ill <https://doi.org/10.1109/EWME.2016.7496466>

Topological analysis of SSBDDs with applications in fault diagnosis

Ubar, Raimund-Johannes Proceedings of 10th International Workshop on Boolean Problems : Freiberg, Germany, September 19-21, 2012 2012 / p. 1-16

Towards artificial intelligence based automatic adaptive response analyzer for high frequency analog BIST

Petlenkov, Eduard; Jutman, Artur; Nõmm, Sven; Ubar, Raimund-Johannes CIMSA 2008 : IEEE International Conference on Computational Intelligence for Measurement Systems and Applications : Istanbul, Turkey, July 14-16, 2008 2008 / p. 99-104 : ill <https://ieeexplore.ieee.org/document/4595841>

Transient modeling and recovery of non-stationary fault signature for condition monitoring of induction motors

Asad, Bilal; Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants; Rassõlkin, Anton; Shams Ghahfarokhi, Payam Advances in machine fault diagnosis 2022 / p. 43-59 <https://doi.org/10.3390/app11062806>

Transient modeling and recovery of non-stationary fault signature for condition monitoring of induction motors

Asad, Bilal; Vaimann, Toomas; Belahcen, Anouar; Kallaste, Ants; Rassõlkin, Anton; Shams Ghahfarokhi, Payam; Kudelina, Karolina Applied sciences 2021 / 17 p. : ill <https://doi.org/10.3390/app11062806> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Transition delay fault simulation with parallel critical path back-tracing and 7-valued algebra

Kõusaar, Jaak; Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan Microprocessors and microsystems 2015 / p. 1130-1138 : ill <https://doi.org/10.1016/j.micpro.2015.05.003> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Troubleshooting and debugging functions

Ruban, Olga; Laugis, Juhan 5th International Symposium "Topical Problems in the Field of Electrical and Power Engineering". Doctoral School of Energy and Geotechnology : Kuressaare, January 14-19, 2008 2008 / p. 216-221 : ill

Troubleshooting process analysis and development of application for decision making enhancement

Mahmood, Kashif; Ševtšenko, Eduard; Karaulova, Tatjana; Branten, Eva; Maleki, Meysam 26th DAAAM International Symposium on Intelligent Manufacturing and Automation 2015 (DAAAM 2015) : Zadar, Croatia, 21-24 October 2015. Volume 1 2016 / p. 0663-0671 : ill <http://dx.doi.org/10.2507/26th.daaam.proceedings.090>

A 2D FEM model for transient and fault analysis of induction machines

Martinez, Javier; **Belahcen, Anouar**; Arkkio, Antero Przegląd elektrotechniczny = Electrical review 2012 / p. 157-160 : ill <http://pe.org.pl/articles/2012/7b/41.pdf>

Tõrked, vead ja rikked ning süsteemide usaldusväärsus

Paluoja, Rein; Petermann, Viktor A & A 1998 / 3, lk. 16-21: ill

Ultra fast parallel fault analysis on structurally synthesized BDDs

Ubar, Raimund-Johannes; Devadze, Sergei; Raik, Jaan; Jutman, Artur 12th IEEE European Test Symposium ETS 2007 : 20-24 May 2007, Freiburg, Germany : proceedings 2007 / p. 131-136 : ill <http://dx.doi.org/10.1109/ETS.2007.43>

Understanding fault-tolerance vulnerabilities in advanced SoC FPGAs for critical applications

Cherezova, Natalia; Shibin, Konstantin; Jenihhin, Maksim; Jutman, Artur Microelectronics reliability 2023 / art. 115010, 10 p. : ill <https://doi.org/10.1016/j.microrel.2023.115010> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

Understanding MPSoCs : exploiting memory microarchitectural vulnerabilities of high performance NoC-based MPSoCs

Sepulveda, Johanna; **Azad, Siavoosh Payandeh; Niazmand, Behrad; Jervan, Gert** SAMOS '18 : Proceedings of the 18th International Conference on Embedded Computer Systems: Architectures, Modeling, and Simulation, Pythagorion, Greece, July 15-19, 2018 2018 / p. 162-166 <https://doi.org/10.1145/3229631.3239367> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)

Untestable fault identification in sequential circuits using model-checking

Raik, Jaan; Fujiwara, Hideo; Ubar, Raimund-Johannes; Krivenko, Anna 2002-2011 : 20th Anniversary compendium of papers from Asian Test Symposium 2011 / p. 257-262 : ill <https://ieeexplore.ieee.org/document/4711554>

Untestable fault identification in sequential circuits using model-checking

Raik, Jaan; Fujiwara, Hideo; Ubar, Raimund-Johannes; Krivenko, Anna Proceedings of the 17th Asian Test Symposium ATS 2008 : November 24-27, 2008, Sapporo, Japan 2008 / p. 21-26 : ill <http://dx.doi.org/10.1109/ATS.2008.22>

Uuenduslik metoodika aitab võidelda elektrisüsteemi rike

Andreesen, Guido novaator.err.ee 2024 [Uuenduslik metoodika aitab võidelda elektrisüsteemi rike](#)

Uuendusliku metoodikaga elektrisüsteemi rikete vastu

Andreesen, Guido TööstusEST 2024 / lk. 67 : portr https://www.ester.ee/record=b4481084*est

Validation of full-converter wind power plant generic model based on actual fault ride-through measurements

Tšernobrovkin, Oleg; Perdana, Abram; Palu, Ivo; Kilter, Jako Journal of energy and power engineering 2010 / 4, p. 54-62

Web-based framework for parallel distributed test [Electronic resource]

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes 2008 IEEE Design and Diagnostics of Electronic Circuits and Systems : Bratislava, Slovakia, April 16-18, 2008 2008 / p. 271-274 : ill. [CD-ROM] <https://ieeexplore.ieee.org/document/4538800>

Veepuhastusjaama juurdevoolukanalis toimunud avarii põhjustest

Jaaniso, Valdo Ehitaja 1998 / lk. 86-87, 89: ill https://www.ester.ee/record=b1072123*est

Verification of a wind farm aggregated generic dynamic model based on a real fault ride-through test in the grid

Tšernobrovkin, Oleg; Perdana, Abram; Palu, Ivo; Kilter, Jako Proceedings of 5th Nordic Wind Power Conference 2009 2009 / [6] p <https://research.chalmers.se/en/publication/97817>

Vibration and stator current spectral analysis of induction machine operating under dynamic eccentricity

Sobra, Jan; Belahcen, Anouar; Vaimann, Toomas 2015 International Conference on Electrical Drives and Power Electronics (EDPE) : 18th International Conference, 7th Joint Slovakian-Croatian Conference : proceedings : Hotel Slovan, Tatranska Lomnica, The High Tatras, Slovakia, September 21-23, 2015 2015 / p. 285-290 : ill <http://dx.doi.org/10.1109/EDPE.2015.7325307>

Vibration as fault indicator in electrical machines

Farzam Far, Mehmaz; Belahcen, Anouar; Arkkio, Antero; Roivainen, Janne Doctoral School of Energy and Geotechnology II : closing conference of the project : Pärnu, Estonia, January 12-17, 2015 2015 / p. 120-125 : ill

Winding function based analytical model of squirrel cage induction motor for fault diagnostics

Asad, Bilal; Vaimann, Toomas; Kallaste, Ants; Rassõlkin, Anton; Belahcen, Anouar 2019 26th International Workshop on Electric Drives : Improvement in Efficiency of Electric Drives (IWED) : Moscow Power Engineering Institute, Moscow, Russia, 30th of January - 2nd of February 2019 : proceedings 2019 / 6 p. : ill <https://doi.org/10.1109/IWED.2019.8664314>

Wound core voltage transformers overvoltage problems caused by single phase faults in MV networks

Järvik, Jaan; Kalda, Heljut; Külm, Evald; Sepping, Eino; Choi, J. Международная научно-техническая конференция "Перенапряжения и надежность эксплуатации электрооборудования" : Санкт-Петербург, 31 марта - 05 апреля 2003 г. Выпуск 1 2003 / p. 324-332 : ill

Алгоритм оценки качества вероятностного тестирования цифровых схем

Grigorjeva, Ksenja Машинное проектирование электронных устройств и систем 1989 / с. 97-103

Анализ процессов нагрузки и выявление неисправностей городских таксофонов

Animägi, T.; Borštševski, A.I.; Kangur, Oleg Методы цифровой обработки и хранения радиотехнических сигналов 1987 / с. 99-105

Вероятностное тестирование цифровых схем и альтернативные графы

Ubar, Raimund-Johannes Машинное проектирование электронных устройств и систем 1989 / с. 89-96

Влияние импеданса ключей на погрешности коммутируемых индуктивных делителей напряжения

Peterson, Jaak Расчет и проектирование измерительных преобразователей 1983 / с. 11-17 : ил https://www.ester.ee/record=b1288985*est <https://digikogu.taltech.ee/et/Item/4e3815a3-f217-4ae2-9776-1b5ea3c25959>

Диагностика кратных неисправностей в комбинационных схемах

Viilup, Agu; Ubar, Raimund-Johannes; Heiter, U. Труды по электротехнике и автоматике : сборник статей. 11 1973 / с. 89-94 : илл https://www.ester.ee/record=b2190624*est <https://digikogu.taltech.ee/et/Item/d6e57925-e104-44e1-a218-c5b3110d9996>

Из-за перебоев с электричеством у многих жителей Эстонии поломалась бытовая техника. Кто выплатит компенсацию?

Карпи, А-М. rus.postimees.ee 2024 [Из-за перебоев с электричеством у многих жителей Эстонии поломалась бытовая техника. Кто выплатит компенсацию?](#)

Индикатор неисправности ламп ближнего света в автомобиле

Gavrilov, Aleksei Радиолюбитель 2016 / с. 11

К вычислению изменения интенсивности отказов элементов по изменениям температуры и нагрузки

Koort, Ants Тезисы докладов Республиканской научно-технической конференции "Современные методы и устройства радиоэлектронного оборудования", посвященной Дню радио. [2], Секция: Компьютерный анализ сигналов и цепей 1981 / с. 9-10 https://www.ester.ee/record=b1310795*est

Метод диагноза неисправностей в последовательностных системах

Grigorjeva, Ksenja; Ubar, Raimund-Johannes Расчет и проектирование приборов, устройств и систем технической кибернетики 1980 / с. 35-44 https://www.ester.ee/record=b1281890*est <https://digikogu.taltech.ee/et/Item/8e0abfe2-9020-4ebd-85d1-fd67de0d1b30>

Минимизация ошибок в лазерном рециркуляционном дальномере

Zahharov, Boriss; Krusell, Urmas Тезисы докладов III Всесоюзной конференции "Применение лазеров в технологии и системах передачи и обработки информации", 11-13 ноября 1987 г. 3, Лазерные системы передачи и обработки информации 1987 / с. 25 https://www.ester.ee/record=b1273195*est

Низкочастотные погрешности автотрансформаторных делителей напряжения

Jöers, Rein Расчет и проектирование приборов, устройств и систем технической кибернетики 1980 / с. 73-80 : илл https://www.ester.ee/record=b1264145*est <https://digikogu.taltech.ee/et/Item/81bf2178-a9f8-417d-86c7-2000cca6a01e>

О минимизации среднего времени обнаружения неисправностей в технических устройствах

Ubar, Raimund-Johannes; Maslennikov, V.P. Вопросы управления процессами. Ч.1 1971 / с. 136-142

Описание неисправностей цифровых устройств

Ubar, Raimund-Johannes Расчет и проектирование приборов, устройств и систем технической кибернетики 1980 / с. 3-9 : илл https://www.ester.ee/record=b1264145*est <https://digikogu.taltech.ee/et/Item/81bf2178-a9f8-417d-86c7-2000cca6a01e>

Описание постоянных неисправностей ЦВМ

Viilup, Agu Расчет и проектирование приборов, устройств и систем технической кибернетики 1980 / с. 69-77 https://www.ester.ee/record=b1281890*est <https://digikogu.taltech.ee/et/Item/8e0abfe2-9020-4ebd-85d1-fd67de0d1b30>

Определение места повреждения в сетях 6...35 кВ при однофазных замыканиях на землю

Ranov, Valeri; Järvik, Jaan Ограничение перенапряжений и режимы заземления нейтрали сетей 6-35 кВ : труды третьей всероссийской научно-технической конференции : 28-30 сентября 2004 года 2004 / с. 160-167 : ил

Организация обработки ошибок в системе построения трансляторов

Vooglaid, Aare; Rohtla, Hanno Анализ данных. Построение трансляторов. Вопросы программирования 1978 / с. 83-92 https://www.ester.ee/record=b1272492*est <https://digikogu.taltech.ee/et/Item/1dbbc143-d62a-4471-af6c-c660a4af0827>

Построение тестов для неисправностей комбинационных схем на основе анализа ортогональных дизъюнктивных нормальных форм, представляемых альтернативными графами

Matrosova, A.Yu.; Pleshkov, A.G.; Ubar, Raimund-Johannes Автоматика и телемеханика 2005 / с. 158-174 : ил <http://mi.mathnet.ru/at1333>

Профессор Алар Конист: такими темпами о дешевом электричестве можно забыть

Konist, Alar dv.ee 2025 <https://www.dv.ee/novosti/2025/05/05/professor-alar-konist-takimi-tempami-o-deshevom-jelektrichestve-mozhno-zabyt>

Стохастическое моделирование на ЭЦВМ возникновения отказов при малых нагрузках

Koort, Ants Тезисы докладов научно-технической конференции, посвященной Дню радио 1974 / с. 15-16 https://www.ester.ee/record=b1294751*est

Строитель Аувереской электростанции выплатил Enefit Power штраф в размере 130 млн евро

stena.ee 2022 [Строитель Аувереской электростанции выплатил Enefit Power штраф в размере 130 млн евро](#)